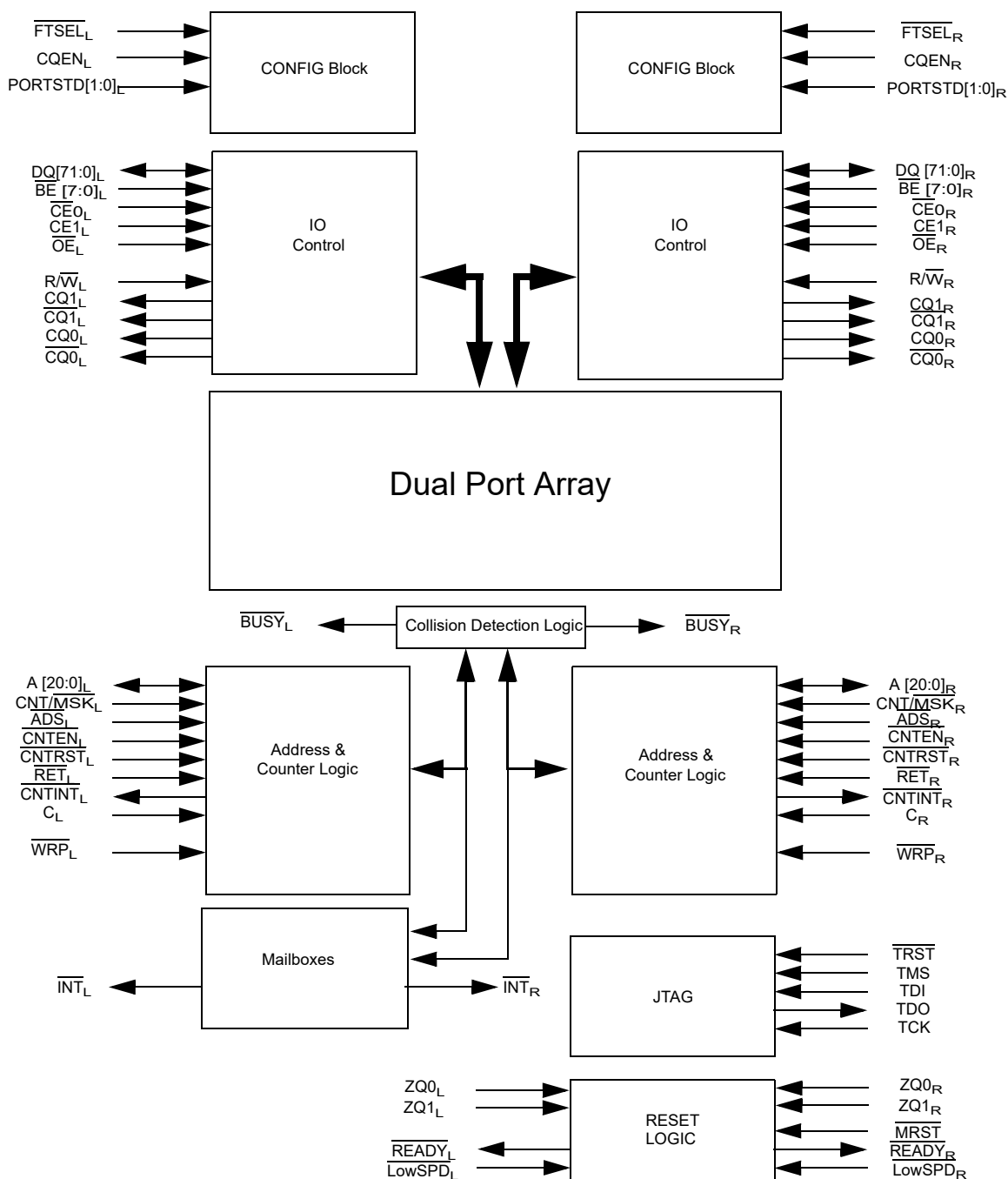


Logic Block Diagram

The Logic Block Diagrams for the FullFlex72, FullFlex36, and FullFlex18 families follow.^[2, 3, 4]



Notes

- The CYD36S18V18 device has 21 address bits. The CYD36S36V18 and CYD18S18V18 devices have 20 address bits. The CYD36S72V18, CYD18S36V18, and CYD09S18V18 devices have 19 address bits. The CYD18S72V18 and CYD09S36V18 devices have 18 address bits. The CYD09S72V18 device has 17 address bits. The CYD02S36V18 has 16 address bits.
- The FullFlex72 family of devices has 72 data lines. The FullFlex36 family of devices has 36 data lines. The FullFlex18 family of devices has 18 data lines.
- The FullFlex72 family of devices has eight byte enables. The FullFlex36 family of devices has four byte enables. The FullFlex18 family of devices has two byte enables.

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Figure 1. FullFlex72 SDR 484-ball BGA Pinout (Top View)

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22
A	DNU	DQ61L	DQ59L	DQ57L	DQ54L	DQ51L	DQ48L	DQ45L	DQ42L	DQ39L	DQ36L	DQ33R	DQ39R	DQ42R	DQ45R	DQ48R	DQ51R	DQ54R	DQ57R	DQ59R	DQ61R	DNU
B	DQ63L	DQ62L	DQ60L	DQ58L	DQ55L	DQ52L	DQ49L	DQ46L	DQ43L	DQ40L	DQ37L	DQ37R	DQ40R	DQ43R	DQ46R	DQ49R	DQ52R	DQ55R	DQ58R	DQ60R	DQ62R	DQ63R
C	DQ65L	DQ64L	VSS	VSS	DQ56L	DQ53L	DQ50L	DQ47L	DQ44L	DQ41L	DQ38L	DQ38R	DQ41R	DQ44R	DQ47R	DQ50R	DQ53R	DQ56R	VSS	VSS	DQ64R	DQ65R
D	DQ67L	DQ66L	VSS	VSS	VSS	<u>Q01L</u>	CQ1L	VSS	<u>LOWSPDL</u>	<u>PORTSTD0L</u>	<u>ZQ0L</u> ^[5]	<u>BUSYL</u>	<u>QNTINTL</u>	<u>PORTSTD1L</u>	DNU	CQ1R	<u>Q01R</u>	VSS	VSS	VSS	DQ66R	DQ67R
E	DQ69L	DQ68L	VDDIOL	VSS	VSS	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VTTL	VTTL	VTTL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	DQ68R	DQ69R
F	DQ71L	DQ70L	CE1L	<u>CE0L</u>	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	DQ70R	DQ71R
G	A0L	A1L	<u>RETL</u>	<u>BE4L</u>	VDDIOL	VDDIOL	VREFL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VREFR	VDDIOL	VDDIOL	<u>BE4R</u>	<u>RETR</u>	A1R	A0R
H	A2L	A3L	<u>WRPL</u>	<u>BE5L</u>	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>BE5R</u>	<u>WRPR</u>	A3R	A2R
J	A4L	A5L	<u>READYL</u>	<u>BE6L</u>	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>BE6R</u>	<u>READYR</u>	A5R	A4R
K	A6L	A7L	<u>ZQ1L</u> ^[5, 6]	<u>BE7L</u>	VTTL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>BE7R</u>	<u>ZQ1R</u> ^[5, 6]	A7R	A6R
L	A8L	A9L	CL	<u>OE1L</u>	VTTL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>OE1R</u>	CR	A9R	A8R
M	A10L	A11L	VSS	<u>BE3L</u>	VTTL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>BE3R</u>	VSS	A11R	A10R
N	A12L	A13L	<u>ADSL</u>	<u>BE2L</u>	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>BE2R</u>	<u>ADSR</u>	A13R	A12R
P	A14L	A15L	<u>CNT/MSKL</u>	<u>BE1L</u>	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>BE1R</u>	<u>CNT/MSKR</u>	A15R	A14R
R	A16L ^[9]	A17L ^[8]	<u>CNTENL</u>	<u>BE0L</u>	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>BE0R</u>	<u>CNTENR</u>	A17R ^[8]	A16R ^[9]
T	A18L ^[7]	DNU	<u>CNTRSTL</u>	<u>INTL</u>	VDDIOL	VDDIOL	VREFL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>INTR</u>	<u>CNTRSTR</u>	DNU	A18R ^[7]
U	DQ35L	DQ34L	R ^W L	CQENL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	CQENR	R ^W R	DQ34R	DQ35R
V	DQ33L	DQ32L	<u>FTSELL</u>	VDDIOL	DNU	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VTTL	VTTL	VTTL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	<u>FTSELR</u>	VDDIOL	DQ32R	DQ33R
W	DQ31L	DQ30L	VSS	<u>MRST</u>	VSS	<u>Q00L</u>	CQ0L	DNU	<u>PORTSTD1R</u>	<u>CNTINTR</u>	<u>BUSYR</u>	<u>ZQ0R</u> ^[5]	<u>PORTSTD0R</u>	<u>LOWSPDR</u>	VSS	CQ0R	<u>Q00R</u>	VSS	TDI	TDO	DQ30R	DQ31R
Y	DQ29L	DQ28L	VSS	VSS	DQ20L	DQ17L	DQ14L	DQ11L	DQ8L	DQ5L	DQ2L	DQ2R	DQ9R	DQ8R	DQ11R	DQ14R	DQ17R	DQ20R	TMS	TCK	DQ28R	DQ29R
AA	DQ27L	DQ26L	DQ24L	DQ22L	DQ19L	DQ16L	DQ13L	DQ10L	DQ7L	DQ4L	DQ1L	DQ1R	DQ4R	DQ7R	DQ10R	DQ13R	DQ16R	DQ19R	DQ22R	DQ24R	DQ26R	DQ27R
AB	DNU	DQ25L	DQ23L	DQ21L	DQ18L	DQ15L	DQ12L	DQ9L	DQ6L	DQ3L	DQ0L	DQ0R	DQ3R	DQ6R	DQ9R	DQ12R	DQ15R	DQ18R	DQ21R	DQ23R	DQ25R	DNU

Notes

5. Leave this ball unconnected to disable VIM.
6. This ball is applicable only for 36-Mbit and DNU for 18-Mbit and lower densities.
7. Leave this ball unconnected for CYD18S72V18 and CYD09S72V18.
8. Leave this ball unconnected for CYD09S72V18.
9. Leave this ball unconnected for CYD04S72V18.



Figure 2. FullFlex36 SDR 484-ball BGA Pinout (Top View)^[10]

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22
A	DNU	DNU	DNU	DNU	DNU	DQ33L	DQ30L	DQ27L	DQ24L	DQ21L	DQ18L	DQ19R	DQ21R	DQ24R	DQ27R	DQ30R	DQ33R	DNU	DNU	DNU	DNU	DNU
B	DNU	DNU	DNU	DNU	DNU	DQ34L	DQ31L	DQ28L	DQ25L	DQ22L	DQ19L	DQ19R	DQ22R	DQ25R	DQ28R	DQ31R	DQ34R	DNU	DNU	DNU	DNU	DNU
C	DNU	DNU	VSS	VSS	DNU	DQ35L	DQ32L	DQ29L	DQ26L	DQ23L	DQ20L	DQ20R	DQ23R	DQ26R	DQ29R	DQ32R	DQ35R	DNU	VSS	VSS	DNU	DNU
D	DNU	DNU	VSS	VSS	VSS	CQ1L	CQ1L	VSS	LOWSPDL	PORTSTD0L	ZQ0L ^[11]	BUSYL	CNTINTL	PORTSTD1L	DNU	CQ1R	CQ1R	VSS	VSS	VSS	DNU	DNU
E	DNU	DNU	VDDIOL	VSS	VSS	VDDIOL	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VTTL	VTTL	VTTL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	DNU	VSS	VDDIOR	DNU	DNU
F	DNU	DNU	CE1L	CE0L	VDDIOL	VDDIOL	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	CE0R	CE1R	DNU	DNU
G	A0L	A1L	RETL	BE2L	VDDIOL	VDDIOL	VREFL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VREFR	VDDIOR	VDDIOR	BE2R	RETR	A1R	A0R
H	A2L	A3L	WRPL	BE3L	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	VDDIOR	BE3R	WRPR	A3R	A2R
J	A4L	A5L	READYL	DNU	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	VDDIOR	DNU	READYR	A5R	A4R
K	A6L	A7L	ZQ1L ^[11]	DNU	VTTL	VCORE	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VCORE	VDDIOR	DNU	ZQ1R ^[11]	A7R	A6R
L	A8L	A9L	CL	OEL	VTTL	VCORE	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VCORE	VTTL	OER	CR	A9R	A8R
M	A10L	A11L	VSS	DNU	VTTL	VCORE	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VCORE	VTTL	DNU	VSS	A11R	A10R
N	A12L	A13L	ADSL	DNU	VDDIOL	VCORE	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VCORE	VTTL	DNU	ADSR	A13R	A12R
P	A14L	A15L	CNTMSKL	BE1L	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	VDDIOR	BE1R	CNTMSKR	A15R	A14R
R	A16L	A17L	CNTENL	BE0L	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	VDDIOR	BE0R	CNTENR	A17R	A16R
T	A18L	A19L	CNTRSTL	INTL	VDDIOL	VDDIOL	VREFL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VREFR	VDDIOR	VDDIOR	INTR	CNTRSTR	A19R	A18R
U	DNU	DNU	RWL	CQENL	VDDIOL	VDDIOL	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VDDIOR	CQENR	RWR	DNU	DNU
V	DNU	DNU	FTSELL	VDDIOL	DNU	VDDIOR	VDDIOR	VDDIOR	VDDIOR	VTTL	VTTL	VTTL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOR	TRST	FTSELR	DNU	DNU	DNU
W	DNU	DNU	VSS	MRST	VSS	CQ0L	CQ0L	DNU	PORTSTD1R	CNTINTR	BUSYR	ZQ0R ^[11]	PORTSTD0R	LOWSPDR	VSS	CQ0R	CQ0R	VSS	TDI	TDI	DNU	DNU
Y	DNU	DNU	VSS	VSS	DNU	DQ17L	DQ14L	DQ11L	DQ8L	DQ5L	DQ2L	DQ2R	DQ5R	DQ8R	DQ11R	DQ14R	DQ17R	DNU	TMS	TCK	DNU	DNU
AA	DNU	DNU	DNU	DNU	DNU	DQ16L	DQ13L	DQ10L	DQ7L	DQ4L	DQ1L	DQ1R	DQ4R	DQ7R	DQ10R	DQ13R	DQ16R	DNU	DNU	DNU	DNU	DNU
AB	DNU	DNU	DNU	DNU	DNU	DQ15L	DQ12L	DQ9L	DQ6L	DQ3L	DQ0L	DQ0R	DQ3R	DQ6R	DQ9R	DQ12R	DQ15R	DNU	DNU	DNU	DNU	DNU

Notes

10. Use this pinout only for the CYD36S36V18 device of the FullFlex36 family.

11. Leave this ball unconnected to disable VIM.



Figure 3. FullFlex18 SDR 484-ball BGA Pinout (Top View)^{[1][2]}

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21	22
A	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DQ15L	DQ12L	DQ9L	DQ8R	DQ12R	DQ15R	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DNU
B	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DQ16L	DQ13L	DQ10L	DQ10R	DQ13R	DQ16R	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DNU
C	DNU	DNU	VSS	VSS	DNU	DNU	DNU	DNU	DQ17L	DQ14L	DQ11L	DQ11R	DQ14R	DQ17R	DNU	DNU	DNU	DNU	VSS	VSS	DNU	DNU
D	DNU	DNU	VSS	VSS	VSS	<u>Q01L</u>	<u>Q01L</u>	VSS	<u>LOWSPDL</u>	<u>PORTSTD0L</u>	<u>Z00L</u> ^[13]	<u>BUSYL</u>	<u>CNTINTL</u>	<u>PORTSTD1L</u>	DNU	<u>CQ1R</u>	<u>CQ1R</u>	VSS	VSS	VSS	DNU	DNU
E	DNU	DNU	VDDIOL	VSS	VSS	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VTTL	VTTL	VTTL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	DNU	VDDIOL	VDDIOL	DNU	DNU
F	DNU	DNU	CE1L	<u>CE0L</u>	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	<u>CE0R</u>	<u>CE1R</u>	DNU	DNU
G	A0L	A1L	<u>RET1L</u>	<u>BET1L</u>	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VREFR	VDDIOL	VDDIOL	<u>BETR</u>	<u>RETR</u>	A1R	A0R
H	A2L	A3L	<u>WRP1L</u>	DNU	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	DNU	<u>WRP1R</u>	A3R	A2R
J	A4L	A5L	<u>READY1L</u>	DNU	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	DNU	<u>READY1R</u>	A5R	A4R
K	A6L	A7L	<u>ZQ1L</u> ^[13]	DNU	VTTL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	DNU	<u>ZQ1R</u> ^[13]	A7R	A6R
L	A8L	A9L	CL	<u>OEL</u>	VTTL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>OER</u>	CR	A9R	A8R
M	A10L	A11L	VSS	DNU	VTTL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	DNU	VSS	A11R	A10R
N	A12L	A13L	<u>ADSL</u>	DNU	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	DNU	<u>ADSR</u>	A13R	A12R
P	A14L	A15L	<u>CNTMSKL</u>	DNU	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	DNU	<u>CNTMSKR</u>	A15R	A14R
R	A16L	A17L	<u>CNTENL</u>	<u>BE0L</u>	VDDIOL	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOL	VDDIOL	<u>BE0R</u>	<u>CNTENR</u>	A17R	A16R
T	A18L	A19L	<u>CNTRSTL</u>	<u>INTL</u>	VDDIOL	VDDIOL	VREFL	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VSS	VREFR	VDDIOL	VDDIOL	<u>INTR</u>	<u>CNTRSTR</u>	A19R	A18R
U	A20L	DNU	<u>RWL</u>	<u>CQENL</u>	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	<u>CQENR</u>	<u>RWR</u>	DNU	A20R
V	DNU	DNU	<u>FTSELL</u>	VDDIOL	DNU	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VTTL	VTTL	VTTL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	VDDIOL	<u>TRST</u>	VDDIOL	<u>FTSELR</u>	DNU	DNU
W	DNU	DNU	VSS	<u>MRST</u>	VSS	<u>Q00L</u>	<u>Q00L</u>	DNU	<u>PORTSTD1R</u>	<u>CNTINTR</u>	<u>BUSYR</u>	<u>Z00R</u> ^[13]	<u>PORTSTD0R</u>	<u>LOWSPDR</u>	VSS	<u>CQ0R</u>	<u>CQ0R</u>	VSS	TDI	TDI	DNU	DNU
Y	DNU	DNU	VSS	VSS	DNU	DNU	DNU	DNU	DQ8L	DQ5L	DQ2L	DQ2R	DQ5R	DQ8R	DNU	DNU	DNU	DNU	TMS	TCK	DNU	DNU
AA	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DQ7L	DQ4L	DQ1L	DQ1R	DQ4R	DQ7R	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DNU
AB	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DQ6L	DQ3L	DQ0L	DQ0R	DQ3R	DQ6R	DNU	DNU	DNU	DNU	DNU	DNU	DNU	DNU

Notes

- Use this pinout only for device CYD36S18V18 of the FullFlex18 family.
- Leave this ball unconnected to disable VIM.



Figure 4. FullFlex36 SDR 256-ball BGA (Top View)

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
A	DQ32L	DQ30L	DQ28L	DQ26L	DQ24L	DQ22L	DQ20L	DQ18L	DQ16R	DQ20R	DQ22R	DQ24R	DQ26R	DQ28R	DQ30R	DQ32R
B	DQ33L	DQ31L	DQ29L	DQ27L	DQ25L	DQ23L	DQ21L	DQ19L	DQ19R	DQ21R	DQ23R	DQ25R	DQ27R	DQ29R	DQ31R	DQ33R
C	DQ34L	DQ35L	RET _L	INT _L	CQ1L	CQ1L	DNU	TRST	MRST	ZQ0R ^[14]	CQ1R	CQ1R	INTR	RETR	DQ35R	DQ34R
D	A0L	A1L	WRPL	VREFL	FTSELL	LOWSPDL	VSS	VTTL	VTTL	VSS	LOWSPDR	FTSEL _R	VREFR	WRPR	A1R	A0R
E	A2L	A3L	CE0L	CE1L	VDDIOL	VDDIOL	VDDIOL	VCORE	VCORE	VDDIOR	VDDIOR	VDDIOR	CE1R	CE0R	A3R	A2R
F	A4L	A5L	CNTINTL	BE3L	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	BE3R	CNTINTR	A5R	A4R
G	A6L	A7L	BUSYL	BE2L	ZQ0L ^[14]	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	BE2R	BUSYR	A7R	A6R
H	A8L	A9L	CL	VTTL	VCORE	VSS	VSS	VSS	VSS	VSS	VSS	VCORE	VTTL	CR	A9R	A8R
J	A10L	A11L	VSS	PORTSTD1L	VCORE	VSS	VSS	VSS	VSS	VSS	VSS	VCORE	PORTSTD1R	VSS	A11R	A10R
K	A12L	A13L	OEL	BE1L	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	BE1R	OER	A13R	A12R
L	A14L	A15L	ADSL	BE0L	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	BE0R	ADSR	A15R	A14R
M	A16L ^[17]	A17L ^[16]	RWL	CQENL	VDDIOL	VDDIOL	VDDIOL	VCORE	VCORE	VDDIOR	VDDIOR	VDDIOR	CQENR	RWR	A17R ^[16]	A16R ^[17]
N	A18L ^[15]	DNU	CNT/MSKL	VREFL	PORTSTD0L	READYL	DNU	VTTL	VTTL	DNU	READYR	PORTSTD0R	VREFR	CNT/MSKR	DNU	A18R ^[15]
P	DQ16L	DQ17L	CNTENL	CNTRSTL	CQ0L	CQ0L	TCK	TMS	TDO	TDI	CQ0R	CQ0R	CNTRSTR	CNTENR	DQ17R	DQ16R
R	DQ15L	DQ13L	DQ11L	DQ9L	DQ7L	DQ5L	DQ3L	DQ1L	DQ1R	DQ3R	DQ5R	DQ7R	DQ9R	DQ11R	DQ13R	DQ15R
T	DQ14L	DQ12L	DQ10L	DQ8L	DQ6L	DQ4L	DQ2L	DQ0L	DQ0R	DQ2R	DQ4R	DQ6R	DQ8R	DQ10R	DQ12R	DQ14R

Notes

14. Leave this ball unconnected to disable VIM.
15. Leave this ball unconnected for CYD09S36V18 and CYD02S36V18.
16. Leave this ball unconnected for CYD02S36V18.
17. Leave this ball unconnected for CYD02S36V18.



Figure 5. FullFlex18 SDR 256-ball BGA (Top View)

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
A	DNU	DNU	DNU	DQ17L	DQ16L	DQ13L	DQ12L	DQ9L	DQ9R	DQ12R	DQ13R	DQ16R	DQ17R	DNU	DNU	DNU
B	DNU	DNU	DNU	DNU	DQ15L	DQ14L	DQ11L	DQ10L	DQ10R	DQ11R	DQ14R	DQ15R	DNU	DNU	DNU	DNU
C	DNU	DNU	RETL	INTL	CQ1L	CQ1L	DNU	TRST	MRST	ZQ0R ^[18]	CQ1R	CQ1R	INTR	RETR	DNU	DNU
D	A0L	A1L	WRPL	VREFL	FTSELL	LOWSPDL	VSS	VTTL	VTTL	VSS	LOWSPDR	FTSELR	VREFR	WRPR	A1R	A0R
E	A2L	A3L	CE0L	CE1L	VDDIOL	VDDIOL	VDDIOL	VCORE	VCORE	VDDIOR	VDDIOR	VDDIOR	CE1R	CE0R	A3R	A2R
F	A4L	A5L	CNTINTL	DNU	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	DNU	CNTINTR	A5R	A4R
G	A6L	A7L	BUSYL	DNU	ZQ0L ^[18]	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	DNU	BUSYR	A7R	A6R
H	A8L	A9L	CL	VTTL	VCORE	VSS	VSS	VSS	VSS	VSS	VSS	VCORE	VTTL	CR	A9R	A8R
J	A10L	A11L	VSS	PORTSTD1L	VCORE	VSS	VSS	VSS	VSS	VSS	VSS	VCORE	PORTSTD1R	VSS	A11R	A10R
K	A12L	A13L	OEL	BE1L	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	BE1R	OER	A13R	A12R
L	A14L	A15L	ADSL	BE0L	VDDIOL	VSS	VSS	VSS	VSS	VSS	VSS	VDDIOR	BE0R	ADSR	A15R	A14R
M	A16L	A17L	RWL	CQENL	VDDIOL	VDDIOL	VDDIOL	VCORE	VCORE	VDDIOR	VDDIOR	VDDIOR	CQENR	RWR	A17R	A16R
N	A18L ^[20]	A19L ^[19]	CNT/MSKL	VREFL	PORTSTD0L	READYL	DNU	VTTL	VTTL	DNU	READYR	PORTSTD0R	VREFR	CNT/MSKR	A19R ^[19]	A18R ^[20]
P	DNU	DNU	CNTENL	CNTRSTL	CQ0L	CQ0L	TCK	TMS	TDO	TDI	CQ0R	CQ0R	CNTRSTR	CNTENR	DNU	DNU
R	DNU	DNU	DNU	DNU	DQ6L	DQ5L	DQ2L	DQ1L	DQ1R	DQ2R	DQ3R	DQ6R	DNU	DNU	DNU	DNU
T	DNU	DNU	DNU	DQ8L	DQ7L	DQ4L	DQ3L	DQ0L	DQ0R	DQ3R	DQ4R	DQ7R	DQ8R	DNU	DNU	DNU

Notes

18. Leave this ball unconnected to disable VIM.
19. Leave this ball unconnected for CYD09S18V18.
20. Leave this ball unconnected for CYD04S18V18.

Selection Guide

Parameter	-200	-167	Unit
$f_{MAX}^{[22]}$	200	167	MHz
Maximum access time (clock to data)	3.3	4.0	ns
Typical operating current I_{CC}	800 ^[21]	700 ^[21]	mA
Typical standby current for I_{SB3} (both ports CMOS level)	210 ^[21]	210 ^[21]	mA

Pin Definitions

Left Port	Right Port	Description
A[20:0] _L	A[20:0] _R	Address inputs. ^[23]
DQ[71:0] _L	DQ[71:0] _R	Data bus input and output. ^[24]
$\overline{BE}[7:0]_L$	$\overline{BE}[7:0]_R$	Byte select inputs. ^[25] Asserting these signals enables read and write operations to the corresponding bytes of the memory array.
$\overline{BUSY}_L$	$\overline{BUSY}_R$	Port busy output. When there is an address match and both chip enables are active for both ports, an external $\overline{BUSY}$ signal is asserted on the fifth clock cycles from when the collision occurs.
C_L	C_R	Clock signal. Maximum clock input rate is f_{MAX} .
$\overline{CE0}_L$	$\overline{CE0}_R$	Active LOW chip enable input.
$\overline{CE1}_L$	$\overline{CE1}_R$	Active HIGH chip enable input.
$\overline{CQEN}_L$	$\overline{CQEN}_R$	Echo clock enable input. Assert HIGH to enable echo clocking on respective port.
$\overline{CQ0}_L$	$\overline{CQ0}_R$	Echo clock signal output for DQ[35:0] for FullFlex72 devices. Echo clock signal output for DQ[17:0] for FullFlex36 devices. Echo clock signal output for DQ[8:0] for FullFlex18 devices.
$\overline{CQ0}_L$	$\overline{CQ0}_R$	Inverted echo clock signal output for DQ[35:0] for FullFlex72 devices. Inverted echo clock signal output for DQ[17:0] for FullFlex36 devices. Inverted echo clock signal output for DQ[8:0] for FullFlex18 devices.
$\overline{CQ1}_L$	$\overline{CQ1}_R$	Echo clock signal output for DQ[71:36] for FullFlex72 devices. Echo clock signal output for DQ[35:18] for FullFlex36 devices. Echo clock signal output for DQ[17:9] for FullFlex18 devices.
$\overline{CQ1}_L$	$\overline{CQ1}_R$	Inverted echo clock signal output for DQ[71:36] for FullFlex72 devices. Inverted echo clock signal output for DQ[35:18] for FullFlex36 devices. Inverted echo clock signal output for DQ[17:9] for FullFlex18 devices.
ZQ[1:0] _L	ZQ[1:0] _R	VIM output impedance matching input. ^[26] To use, connect a calibrating resistor between ZQ and ground. The resistor must be five times larger than the intended line impedance driven by the dual port. Assert HIGH or leave DNU to disable VIM.
$\overline{OE}_L$	$\overline{OE}_R$	Output enable input. This asynchronous signal must be asserted LOW to enable the DQ data pins during read operations.
$\overline{INT}_L$	$\overline{INT}_R$	Mailbox interrupt flag output. The mailbox permits communications between ports. The upper two memory locations are used for message passing. $\overline{INT}_L$ is asserted LOW when the right port writes to the mailbox location of the left port, and vice versa. An interrupt to a port is deasserted HIGH when it reads the contents of its mailbox.

Notes

21. For 18 Mbit x72 commercial configuration only; refer to [Electrical Characteristics on page 19](#) for complete information.

22. SDR mode with two pipelined stages.

23. The CYD36S18V18 device has 21 address bits. The CYD36S36V18 and CYD18S18V18 devices have 20 address bits. The CYD36S72V18, CYD18S36V18, and CYD09S18V18 devices have 19 address bits. The CYD18S72V18 and CYD09S36V18 devices have 18 address bits. The CYD09S72V18 device has 17 address bits. The CYD02S36V18 has 16 address bits.

24. The FullFlex72 family of devices has 72 data lines. The FullFlex36 family of devices has 36 data lines. The FullFlex18 family of devices has 18 data lines.

25. The FullFlex72 family of devices has eight byte enables. The FullFlex36 family of devices has four byte enables. The FullFlex18 family of devices has two byte enables.

26. The pin ZQ[1] is applicable only for 36 Mbit devices. This pin is DNU for 18 Mbit and lower density devices.

Pin Definitions (continued)

Left Port	Right Port	Description
LowSPD _L	LowSPD _R	Port low speed select input. Assert this pin LOW to disable the DLL. In flow through mode, this pin needs to be asserted low.
PORTSTD[1:0] _L ^[27, 28]	PORTSTD[1:0] _R ^[27, 28]	Port clock/Address/Control/Data/Echo clock/I/O standard select input. Assert these pins LOW/LOW for LVTTL, LOW/HIGH for HSTL, HIGH/LOW for 2.5 V LVCMOS, and HIGH/HIGH for 1.8 V LVCMOS, respectively. These pins are driven by VTTL referenced levels.
R/W _L	R/W _R	Read/Write enable input. Assert this pin LOW to write to, or HIGH to read from the dual port memory array.
READY _L	READY _R	Port DLL ready output. This signal is asserted LOW when the DLL and variable impedance matching circuits complete calibration. This is a wired OR capable output.
CNT/MSK _L	CNT/MSK _R	Port counter/Mask select input. Counter control input.
ADS _L	ADS _R	Port counter address load strobe input. Counter control input.
CNTEN _L	CNTEN _R	Port counter enable input. Counter control input.
CNTRST _L	CNTRST _R	Port counter reset input. Counter control input.
CNTINT _L	CNTINT _R	Port counter interrupt output. This pin is asserted LOW one cycle before the unmasked portion of the counter is incremented to all "1s".
WRP _L	WRP _R	Port counter wrap input. When the burst counter reaches the maximum count, on the next counter increment WRP is set LOW to load the unmasked counter bits to 0. It is set HIGH to load the counter with the value stored in the mirror register.
RET _L	RET _R	Port counter retransmit input. Assert this pin LOW to reload the initial address for repeated access to the same segment of memory.
VREF _L ^[28]	VREF _R ^[28]	Port external HSTL I/O reference input. This pin is left DNU when HSTL is not used.
VDDIO _L	VDDIO _R	Port data I/O power supply.
FTSEL _L	FTSEL _R	Port flow through mode select input. Assert this pin LOW to select flow through mode. Assert this pin HIGH to select Pipelined mode.
MRST		Master reset input. MRST is an asynchronous input signal and affects both ports. Asserting MRST LOW performs all of the reset functions as described in the text. A MRST operation is required at power up. This pin is driven by a VDDIO _L referenced signal.
TMS		JTAG test mode select input. It controls the advance of JTAG TAP state machine. State machine transitions occur on the rising edge of TCK. Operation for LVTTL or 2.5 V LVCMOS.
TDI		JTAG test data input. Data on the TDI input is shifted serially into selected registers. Operation for LVTTL or 2.5 V LVCMOS.
TRST		JTAG reset input. Operation for LVTTL or 2.5 V LVCMOS.
TCK		JTAG test clock input. Operation for LVTTL or 2.5 V LVCMOS.
TDO		JTAG test data output. TDO transitions occur on the falling edge of TCK. TDO is normally tri-stated except when captured data is shifted out of the JTAG TAP. Operation for LVTTL or 2.5 V LVCMOS.
VSS		Ground inputs.
VCORE		Device core power supply.
VTTL		LVTTL power supply.

Notes

27. PORTSTD[1:0]_L and PORTSTD[1:0]_R have internal pull-down resistors.

28. HSTL support and the corresponding tests support has been removed from the device from WW1830. This change does not impact any other functionality.

Functional Overview

Selectable I/O Standard

The FullFlex device families offer the option to choose one of the four port standards for the device. Each port independently selects standards from single-ended HSTL class I, single-ended LVTTTL, 2.5 V LVCMOS, or 1.8 V LVCMOS. The selection of the standard is determined by the PORTSTD pins for each port. These pins must be connected to an LVTTTL power supply. This determines the input clock, address, control, data, and Echo clock standard for each port as shown in Table 1.

Table 1. Port Standard Selection

PORTSTD1	PORTSTD0	I/O Standard
VSS	VSS	LVTTTL
VSS	VTTTL	HSTL
VTTTL	VSS	2.5 V LVCMOS
VTTTL	VTTTL	1.8 V LVCMOS

Clocking

Separate clocks synchronize the operations on each port. Each port has one clock input C. In this mode, all the transactions on the address, control, and data are on the C rising edge. All transactions on the address, control, data input, output, and byte enables occur on the C rising edge.

Table 2. Data Pin Assignment

BE Pin Name	Data Pin Name
$\overline{\text{BE}}[7]$	DQ[71:63]
$\overline{\text{BE}}[6]$	DQ[62:54]
$\overline{\text{BE}}[5]$	DQ[53:45]
$\overline{\text{BE}}[4]$	DQ[44:36]
$\overline{\text{BE}}[3]$	DQ[35:27]
$\overline{\text{BE}}[2]$	DQ[26:18]
$\overline{\text{BE}}[1]$	DQ[17:9]
$\overline{\text{BE}}[0]$	DQ[8:0]

Selectable Pipelined or Flow through Mode

To meet data rate and throughput requirements, the FullFlex families offer selectable pipelined or flow through mode. Echo clocks are not supported in flow through mode and the DLL must be disabled.

Flow through mode is selected by the FTSEL pin. Strapping this pin HIGH selects pipelined mode. Strapping this pin LOW selects flow through mode.

DLL

The FullFlex families of devices have an on-chip DLL. Enabling the DLL reduces the clock to data valid (t_{CD}) time enabling more setup time for the receiving device. In flow through mode, the DLL must be disabled. This is selectable by strapping LowSPD low.

Whenever the operating frequency is altered beyond the Clock Input Cycle to Cycle Jitter specification, reset the DLL, followed by 1024 clocks before any valid operation.

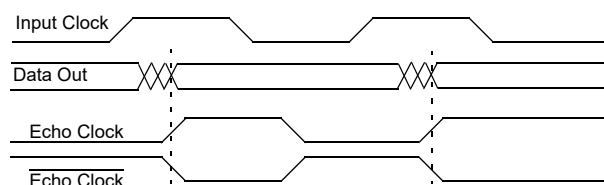
LowSPD pins are used to reset the DLLs for a single port independent of all other circuitry. MRST is used to reset all DLLs on the chip. For more information on DLL lock and reset time, see Master Reset on page 18.

Echo Clocking

As the speed of data increases, on-board delays caused by parasitics make it extremely difficult to provide accurate clock trees. To counter this problem, the FullFlex families incorporate Echo Clocks. Echo Clocks are enabled on a per port basis. The dual port receives input clocks that are used to clock in the address and control signals for a read operation. The dual port retransmits the input clocks relative to the data output. The buffered clocks are provided on the CQ1/CQ1 and CQ0/CQ0 outputs. Each port has a pair of Echo clocks. Each clock is associated with half the data bits. The output clock matches the corresponding ports I/O configuration.

To enable echo clock outputs, tie CQEN HIGH. To disable echo clock outputs, tie CQEN LOW.

Figure 6. SDR Echo Clock Delay



Deterministic Access Control

Deterministic Access Control is provided for ease of design. The circuitry detects when both ports access the same location and provides an external BUSY flag to the port on which data is corrupted. The collision detection logic saves the address in conflict (Busy Address) to a readable register. In the case of multiple collisions, the first busy address is written to the busy address register.

If both ports access the same location at the same time and only one port is doing a write, if t_{CCS} is met, then the data written to and read from the address is valid data. For example, if the right port is reading and the left port is writing and the left ports clock meets t_{CCS} , then the data read from the address by the right port is the old data. In the same case, if the right ports clock meets t_{CCS} , then the data read out of the address from the right port is the new data. In the above case, if t_{CCS} is violated by the either ports clock with respect to the other port and the right port gets the external BUSY flag, the data from the right port is corrupted. Table 3 on page 12 shows the t_{CCS} timing that must be met to guarantee the data.

Table 4 on page 12 shows that, in the case of the left port writing and the right port reading, when an external BUSY flag is asserted on the right port, the data read out of the device is not guaranteed.

The value in the busy address register is read back to the address lines. The required input control signals for this function are shown in Table 7 on page 14. The value in the busy address register is read out to the address lines t_{CA} after the same

amount of latency as a data read operation. After an initial address match, the BUSY flag is asserted and the address under contention is saved in the busy address register. All the following address matches enable to generate the BUSY flag. However,

none of the addresses are saved into the busy address register. When a busy readback is performed, the address of the first match that happens at least two clocks cycles after the busy readback is saved into the busy address register.

Table 3. t_{CCS} Timing for All Operating Modes

Port A - Early Arriving Port		Port B - Late Arriving Port		t_{CCS} C Rise to Opposite C Rise Setup Time for Non Corrupt Data	Unit
Mode	Active Edge	Mode	Active Edge		
SDR	C	SDR	C	$t_{CYC(min)} - 0.5$	ns

Table 4. Deterministic Access Control Logic

Left Port	Right Port	Left Clock	Right Clock	BUSY _L	BUSY _R	Description
Read	Read	X	X	H	H	No collision
Write	Read	$> t_{CCS}$	0	H	H	Read OLD data
		0	$> t_{CCS}$	H	H	Read NEW data
		$< t_{CCS}$	0	H	H	Read OLD data
				H	L	Data not guaranteed
		0	$< t_{CCS}$	H	H	Read NEW data
				H	L	Data Not guaranteed
Read	Write	$> t_{CCS}$	0	H	H	Read NEW data
		0	$> t_{CCS}$	H	H	Read OLD data
		$< t_{CCS}$	0	H	H	Read NEW data
				L	H	Data Not guaranteed
		0	$< t_{CCS}$	H	H	Read OLD data
				L	H	Data not guaranteed
Write	Write	0	$> -t_{CCS} \text{ \& } < t_{CCS}$	L	L	Array data corrupted
		0	$> t_{CCS}$	L	H	Array stores right port data
		$> t_{CCS}$	0	H	L	Array stores left port data

Variable Impedance Matching

Each port contains a variable impedance matching circuit to set the impedance of the I/O driver to match the impedance of the on-board traces. The impedance is set for all outputs except JTAG and is done by port. To take advantage of the VIM feature, connect a calibrating resistor (RQ) that is five times the value of the intended line impedance from the ZQ_[1:0]^[29] pin to V_{SS}. The output impedance is then adjusted to account for drifts in supply voltage and temperature every 1024 clock cycles. If a port's clock is suspended, the VIM circuit retains its last setting until the clock is restarted. On restart, it then resumes periodic adjustment. In the case of a significant change in device temperature or supply voltage, recalibration happens every 1024 clock cycles. A master reset initializes the VIM circuitry. Table 5 shows the VIM parameters and Table 6 describes the VIM operation modes.

To disable VIM, connect the ZQ pin to VDDIO of the relative supply for the I/Os before a Master Reset.

Table 5. Variable Impedance Matching Parameters

Parameter	Min	Max	Unit	Tolerance
RQ value	100	275	Ω	$\pm 2\%$
Output impedance	20	55	Ω	$\pm 15\%$
Reset time	–	1024	Cycles	–
Update time	–	1024	Cycles	–

Table 6. Variable Impedance Matching Operation

RQ Connection	Output Configuration
100 Ω –275 Ω to V _{SS}	Output driver impedance = $RQ/5 \pm 15\%$ at $V_{out} = VDDIO/2$
ZQ to VDDIO	VIM disabled. $R_{out} \leq 20 \Omega$ at $V_{out} = VDDIO/2$

Note

29. The pin ZQ[1] is applicable only for 36 Mbit devices. This pin is DNU for 18 Mbit and lower density devices.

Address Counter and Mask Register Operations ^[30]

Each port of the FullFlex family contains a programmable burst address counter. The burst counter contains four registers: a counter register, a mask register, a mirror register, and a busy address register.

The **counter register** contains the address used to access the RAM array. It is changed only by the master reset (MRST), counter reset, counter load, retransmit, and counter increment operations.

The **mask register** value affects the counter increment and counter reset operations by preventing the corresponding bits of the counter register from changing. It also affects the counter interrupt output (CNTINT). The **mask register** is only changed by mask reset, mask load, and MRST. The mask load operation loads the value of the address bus into the mask register. The mask register defines the counting range of the counter register. The mask register is divided into two or three consecutive regions. Zero or more 0s define the masked region and one or more 1s define the unmasked portion of the counter register. The counter register may be divided up to three regions. The region containing the least significant bits must be no more than two 0s. Bits one and zero may be 10 respectively, masking the least significant counter bit and causing the counter to increment by two instead of one. If bits one and zero are 00, the two least significant bits are masked and the counter increments by four instead of one. For example, in the case of a 256 K × 72 configuration, a mask register value of 003FC divides the mask register into three regions. With bit 0 being the least significant bit and bit 17 being the most significant bit, the two least significant bits are masked, the next eight bits are unmasked, and the remaining bits are masked.

The **mirror register** reloads a counter register on retransmit operations (see [Retransmit on page 15](#)) and wrap functions (see [Counter Interrupt on page 15](#) below). The last value loaded into the counter register is stored in the mirror register. The mirror register is only changed by master reset (MRST), counter reset, and counter load.

[Table 7 on page 14](#) summarizes the operations of these registers and the required input control signals. All signals except MRST are synchronized to the ports clock.

Counter Load Operation ^[30]

For both non-burst and burst read or write accesses, the external address is loaded through counter load operation as shown in [Table 7 on page 14](#). The address counter and mirror registers are loaded with the address value presented on the address lines. This value ranges from 0 to 1FFFFFF.

Mask Load Operation ^[30]

The mask register is loaded with the address value presented on the address bus. This value ranges from 0 to 1FFFFFF though not all values permit correct increment operations. Permitted values are in the form of 2^n-1 , 2^n-2 , or 2^n-4 . The counter register is only segmented up to three regions. From the most significant bit to the least significant bit, permitted values have zero or more 0s, one or more 1s, and the least significant two bits are 11, 10, or 00. Thus 1FFFFFFE, 07FFFF, and 003FFC are permitted values but 02FFFF, 003FFA, and 07FFE4 are not.

Counter Readback Operation

The internal value of the counter register is read out on the address lines. The address is valid t_{CA} after the selected number of latency cycles configured by FTSEL. The data bus (DQ) is tri-stated on the cycle that the address is presented on the address lines. [Figure 7 on page 16](#) shows a block diagram of this logic.

Mask Readback Operation

The internal value of the mask register is read out on the address lines. The address is valid t_{CA} after the selected number of latency cycles configured by FTSEL. The data bus (DQ) is tri-stated on the cycle that the address is presented on the address lines. [Figure 7 on page 16](#) shows a block diagram of the operation.

Counter Reset Operation

All unmasked bits of the counter and mirror registers are reset to '0'. All masked bits remain unchanged. A mask reset followed by a counter reset resets the counter and mirror registers to 00000.

Mask Reset Operation

The mask register is reset to all 1s, that unmask every bit of the burst counter.

Note

30. The CYD36S18V18 device has 21 address bits. The CYD36S36V18 and CYD18S18V18 devices have 20 address bits. The CYD36S72V18, CYD18S36V18, and CYD09S18V18 devices have 19 address bits. The CYD18S72V18 and CYD09S36V18 devices have 18 address bits. The CYD09S72V18 device has 17 address bits. The CYD02S36V18 has 16 address bits.

Table 7. Burst Counter and Mask Register Control Operations

The burst counter and mask register control operation for any port follows. [31, 32]

C	MRST	CNTRST	CNT/MSK	CNTEN	ADS	RET	Operation	Description
X	L	X	X	X	X	X	Master reset	Reset address counter to all 0s, mask register to all 1s, and busy address to all 0s.
	H	L	H	X	X	X	Counter reset	Reset counter and mirror unmasked portion to all 0s.
	H	L	L	X	X	X	Mask reset	Reset mask register to all 1s.
	H	H	H	L	L	X	Counter load for burst/external address load for non-burst	Load burst counter and mirror with external address value presented on address lines.
	H	H	L	L	L	X	Mask load	Load mask register with value presented on the address lines.
	H	H	H	L	H	L	Retransmit	Load counter with value in the mirror register.
	H	H	H	L	H	H	Counter increment	Internally increment address counter value.
	H	H	H	H	H	H	Counter hold	Constantly hold the address value for multiple clock cycles.
	H	H	H	H	L	H	Counter readback	Read out counter internal value on address lines.
	H	H	L	H	L	H	Mask readback	Read out mask register value on address lines.
	H	H	L	H	H	L	Busy address readback	Read out first busy address after last busy address readback.
	H	H	L	L	H	X	Reserved	
	H	H	L	H	L	L	Reserved	
	H	H	L	H	H	H	Reserved	
	H	H	H	H	L	L	Reserved	
	H	H	H	H	H	L	Reserved	

Notes

31. "X" = Don't Care, "H" = HIGH, "L" = LOW.

32. Counter operation and mask register operation is independent of chip enables.

Increment Operation^[33]

After the address counter is initially loaded with an external address, the counter can internally increment the address value and address the entire memory array. Only the unmasked bits of the counter register are incremented. For a counter bit to change, the corresponding bit in the mask register must be 1. If the two least significant bits of the mask register are 11, the burst counter increments by one. If the two least significant bits are 10, the burst counter increments by two, and if they are 00, the burst counter increments by four. If all unmasked counter bits are incremented to 1 and WRP is deasserted, the next increment wraps the counter back to the initially loaded value. The cycle before the increment that results in all unmasked counter bits to become 1s, a counter interrupt flag (CNTINT) is asserted if the counter is incremented again. This increment causes the counter to reach its maximum value and the next increment returns the counter register to its initial value that was stored in the mirror register if WRP is deasserted. If WRP is asserted, the unmasked portion of the counter is filled with 0 instead. The example shown in [Figure 8 on page 17](#) shows an example of the CYDD36S18V18 device with the mask register loaded with a mask value of 00007F unmasking the seven least significant bits. Setting the mask register to this value enables the counter to access the entire memory space. The address counter is then loaded with an initial value of 000005 assuming WRP is deasserted. The masked bits, the seventh address through the twenty-first address, do not increment in an increment operation. The counter address starts at address 000005 and increments its internal address value until it reaches the mask register value of 00007F. The counter wraps around the memory block to location 000005 at the next count. CNTINT is issued when the counter reaches the maximum -1 count.

Hold Operation

The value of all three registers is constantly maintained unchanged for an unlimited number of clock cycles. This operation is useful in applications where wait states are needed or when address is available a few cycles ahead of data in a shared bus interface.

Retransmit

Retransmit enables repeated access to the same block of memory without the need to reload the initial address. An internal mirror register stores the address counter value last loaded. While RET is asserted low, the counter continues to wrap back to the value in the mirror register independent of the state of WRP.

Counter Interrupt

The counter interrupt ($\overline{\text{CNTINT}}$) is asserted LOW one clock cycle before an increment operation that results in the unmasked portion of the counter register being all 1s. It is deasserted by counter reset, counter load, counter increment, mask reset, mask load, and MRST.

Counting by Two

When the two least significant bits of the mask register are 10, the counter increments by two.

Counting by Four

When the two least significant bits of the mask register are 00, the counter increments by four.

Mailbox Interrupts

Use the upper two memory locations for message passing and permit communications between ports. [Table 8 on page 17](#) shows the interrupt operation for both ports. The highest memory location is the mailbox for the right port and the maximum address - 1 is the mailbox for the left port.

When one port writes to the other port's mailbox, the $\overline{\text{INT}}$ flag of the port that the mailbox belongs to is asserted LOW. The $\overline{\text{INT}}$ flag remains asserted until the mailbox location is read by the other port. When a port reads its mailbox, the $\overline{\text{INT}}$ flag is deasserted high after one cycle of latency with respect to the input clock of the port to which the mailbox belongs and is independent of OE.

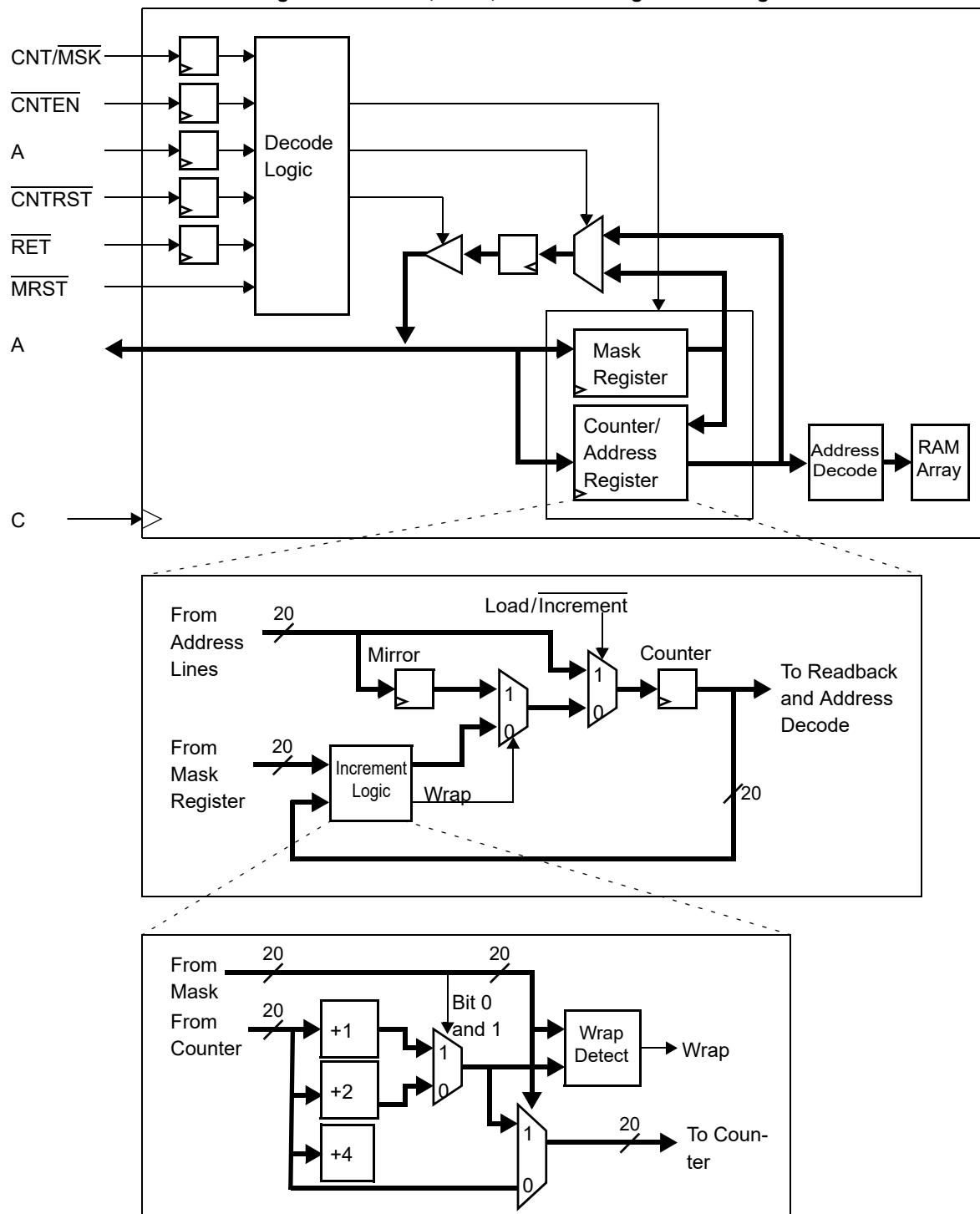
As shown in [Table 8 on page 17](#), to set the $\overline{\text{INT}}_R$ flag, a write operation by the left port to address 1FFFFFF asserts $\overline{\text{INT}}_R$ LOW. A valid read of the 1FFFFFF location by the right port resets $\overline{\text{INT}}_R$ HIGH after one cycle of latency with respect to the right port's clock. You must activate at least one byte enable to set or reset the mailbox interrupt.

Note

33. The CYD36S18V18 device has 21 address bits. The CYD36S36V18 and CYD18S18V18 devices have 20 address bits. The CYD36S72V18, CYD18S36V18, and CYD09S18V18 devices have 19 address bits. The CYD18S72V18 and CYD09S36V18 devices have 18 address bits. The CYD09S72V18 device has 17 address bits. The CYD02S36V18 has 16 address bits.

Figure 7 shows the counter, mask, and mirror logic block diagram. [34]

Figure 7. Counter, Mask, and Mirror Logic Block Diagram



Note

34. The CYD36S18V18 device has 21 address bits. The CYD36S36V18 and CYD18S18V18 devices have 20 address bits. The CYD36S72V18, CYD18S36V18, and CYD09S18V18 devices have 19 address bits. The CYD18S72V18 and CYD09S36V18 devices have 18 address bits. The CYD09S72V18 device has 17 address bits. The CYD02S36V18 has 16 address bits.

Figure 8 shows the programmable counter-mask operation with $\overline{WRP}$ deasserted. [38, 40]

Figure 8. Programmable Counter-Mask Register Operation with $\overline{WRP}$ deasserted

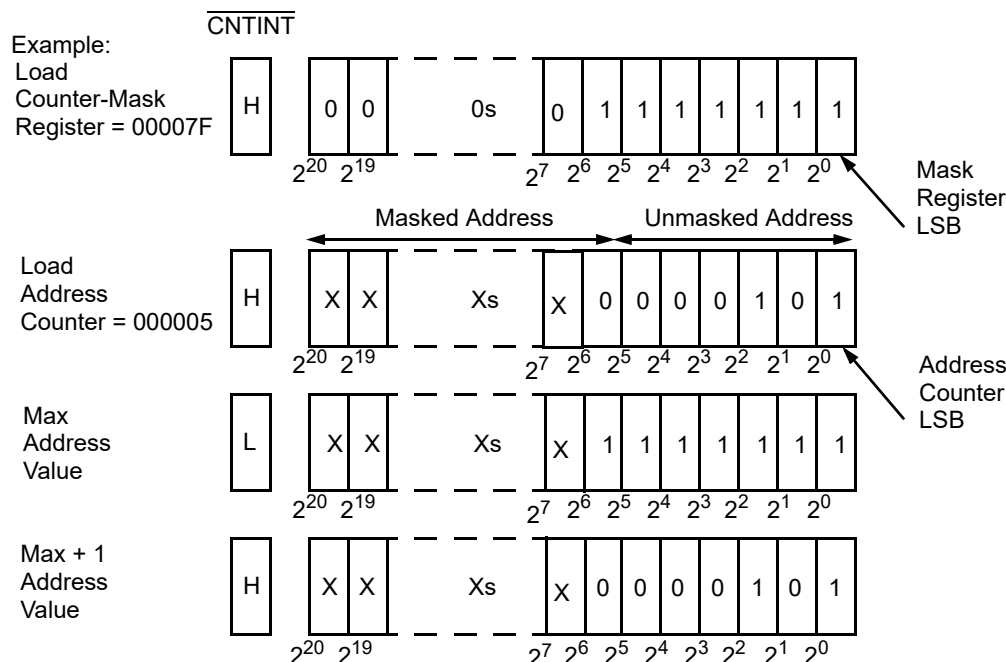


Table 8. Interrupt Operation Example

Table 8 shows the interrupt operation example. [35, 36, 37, 39, 40]

Function	Left Port				Right Port			
	$\overline{R/W}_L$	$\overline{CE}_L$	A_{0L-20L}	$\overline{INT}_L$	$\overline{R/W}_R$	$\overline{CE}_R$	A_{0R-20R}	$\overline{INT}_R$
Set Right $\overline{INT}_R$ Flag	L	L	Max Address	X	X	X	X	L
Reset Right $\overline{INT}_R$ Flag	X	X	X	X	H	L	Max Address	H
Set Left $\overline{INT}_L$ Flag	X	X	X	L	L	L	Max Address-1	X
Reset Left $\overline{INT}_L$ Flag	H	L	Max Address-1	H	X	X	X	X

Notes

35. $\overline{CE}$ is internal signal. $\overline{CE} = \text{LOW}$ if $\overline{CE}_0 = \text{LOW}$ and $\overline{CE}_1 = \text{HIGH}$. For a single read operation, $\overline{CE}$ only needs to be asserted once at the rising edge of the C and is deasserted after that. Data is out after the following C edge and is tri-stated after the next C edge.

36. OE is "Don't Care" for mailbox operation.

37. At least one of BE0, BE1, BE2, BE3, BE4, BE5, BE6, or BE7 must be LOW.

38. The "X" in this diagram represents the counter's upper bits.

39. "X" = Don't Care, "H" = HIGH, "L" = LOW.

40. The CYD36S18V18 device has 21 address bits. The CYD36S36V18 and CYD18S18V18 devices have 20 address bits. The CYD36S72V18, CYD18S36V18, and CYD09S18V18 devices have 19 address bits. The CYD18S72V18 and CYD09S36V18 devices have 18 address bits. The CYD09S72V18 device has 17 address bits. The CYD02S36V18 has 16 address bits.

Master Reset

The FullFlex family of Dual Ports undergoes a complete reset when MRST is asserted. MRST must be driven by VDDIO_L referenced levels. The MRST is asserted asynchronously to the clocks and must remain asserted for at least t_{RS} . When asserted MRST deasserts READY, initializes the internal burst counters, internal mirror registers, and internal busy addresses to zero. It also initializes the internal mask register to all 1s. All mailbox interrupts (INT), busy address outputs (BUSY), and burst counter interrupts (CNTINT) are deasserted upon master reset. Additionally, do not release MRST until all power supplies including VREF are fully ramped and all port clocks and mode select inputs (LOWSPD, ZQ, CQEN, FTSEL, and PORTSTD) are valid and stable. This begins calibration of the DLL and VIM circuits. READY is asserted within 1024 clock cycles. READY is a wired OR capable output with a strong pull up and weak pull down. Up to four outputs may be connected together. For faster pull down of the signal, connect a 250 Ohm resistor to VSS. If the DLL and VIM circuits are disabled for a port, the port is operational within five clock cycles. However, the READY is asserted within 160 clock cycles.

IEEE 1149.1 Serial Boundary Scan (JTAG)

The FullFlex families incorporate an IEEE 1149.1 serial boundary scan test access port (TAP). The TAP operates using JEDEC-standard 3.3 V or 2.5 V I/O logic levels depending on the VTTL power supply. It is composed of four input connections and one output connection required by the test logic defined by the standard.

Table 9. JTAG IDCODE Register Definitions

Part Number	Configuration	Value
CYD36S72V18	512K × 72	0C026069h (× 2)
CYD36S36V18	1024K × 36	0C023069h
CYD36S18V18	2048K × 18	0C024069h
CYD18S72V18	256K × 72	0C025069h
CYD18S36V18	512K × 36	0C026069h
CYD18S18V18	1024K × 18	0C027069h
CYD09S72V18	128K × 72	0C028069h
CYD09S36V18	256K × 36	0C029069h
CYD09S18V18	512K × 18	0C02A069h
CYD02S36V18	64K × 36	0C030069h

Table 10. Scan Registers Sizes

Register Name	Bit Size
Instruction	4
Bypass	1
Identification	32
Boundary Scan	$n^{[41]}$

Table 11. Instruction Identification Codes

Instruction	Code	Description
EXTEST	0000	Captures the input and output ring contents. Places the BSR between the TDI and TDO.
BYPASS	1111	Places the BYR between TDI and TDO.
IDCODE	1011	Loads the IDR with the vendor ID code and places the register between TDI and TDO.
HIGHZ	0111	Places BYR between TDI and TDO. Forces all FullFlex72 and FullFlex36 output drivers to a High Z state.
CLAMP	0100	Controls boundary to 1 or 0. Places BYR between TDI and TDO.
SAMPLE/PRELOAD	1000	Captures the input and output ring contents. Places BSR between TDI and TDO.
RESERVED	All other codes	Other combinations are reserved. Do not use other than the mentioned combinations.

Note

41. Details of the boundary scan length is found in the BSDL file for the device.

Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. User guidelines are not tested.

Storage temperature -65 °C to + 150 °C

Ambient temperature
with power applied -55 °C to + 125 °C

Supply voltage to ground potential -0.5 V to + 4.1 V

DC voltage applied to outputs
in high Z State -0.5 V to $V_{DDIO} + 0.5$ V

DC input voltage -0.5 V to $V_{DDIO} + 0.5$ V

Output current into outputs (LOW) 20 mA

Static discharge voltage
(JEDEC JESD8-6, JESD8-B) > 2200 V

Latch-up current > 200 mA

Operating Range

Range	Ambient Temperature	V _{CORE}
Commercial	0 °C to +70 °C	1.8 V ± 100 mV 1.5 V ± 80 mV
Industrial	-40 °C to +85 °C	1.8 V ± 100 mV 1.5 V ± 80 mV

Power Supply Requirements

	Min	Typ	Max
LVTTL V_{DDIO}	3.0 V	3.3 V	3.6 V
2.5 V LVCMOS V_{DDIO}	2.3 V	2.5 V	2.7 V
HSTL V_{DDIO} ^[44]	1.4 V	1.5 V	1.9 V
1.8 V LVCMOS V_{DDIO}	1.7 V	1.8 V	1.9 V
3.3 V VTTL	3.0 V	3.3 V	3.6 V
2.5 V VTTL	2.3 V	2.5 V	2.7 V
HSTL V_{REF}	0.68 V	0.75 V	0.95 V

Electrical Characteristics

Over the Operating Range

Parameter	Description	Configuration	All Speed Bins			Unit
			Min	Typ	Max	
V_{OH}	Output HIGH voltage ($V_{DDIO} = \text{Min}$, $I_{OH} = -8$ mA)	LVTTL	2.4 ^[42]	—	—	V
	($V_{DDIO} = \text{Min}$, $I_{OH} = -4$ mA)	HSTL (DC) ^[43]	$V_{DDIO} - 0.4$ ^[42]	—	—	V
	($V_{DDIO} = \text{Min}$, $I_{OH} = -4$ mA)	HSTL (AC) ^[43]	$V_{DDIO} - 0.5$ ^[42]	—	—	V
	($V_{DDIO} = \text{Min}$, $I_{OH} = -6$ mA)	2.5 V LVCMOS	1.7 ^[42]	—	—	V
	($V_{DDIO} = \text{Min}$, $I_{OH} = -4$ mA)	1.8 V LVCMOS	$V_{DDIO} - 0.45$ ^[42]	—	—	V
V_{OL}	Output HIGH voltage ($V_{DDIO} = \text{Min}$, $I_{OL} = 8$ mA)	LVTTL	—	—	0.4 ^[42]	V
	($V_{DDIO} = \text{Min}$, $I_{OL} = 4$ mA)	HSTL(DC) ^[43]	—	—	0.4 ^[42]	V
	($V_{DDIO} = \text{Min}$, $I_{OL} = 4$ mA)	HSTL (AC) ^[43]	—	—	0.5 ^[42]	V
	($V_{DDIO} = \text{Min}$, $I_{OL} = 6$ mA)	2.5 V LVCMOS	—	—	0.7 ^[42]	V
	($V_{DDIO} = \text{Min}$, $I_{OL} = 4$ mA)	1.8 V LVCMOS	—	—	0.45 ^[42]	V
V_{IH}	Input HIGH voltage	LVTTL	2	—	$V_{DDIO} + 0.3$	V
		HSTL(DC) ^[43]	$V_{REF} + 0.1$	—	$V_{DDIO} + 0.3$	V
		2.5 V LVCMOS	1.7	—	—	V
		1.8 V LVCMOS	$0.65 \times V_{DDIO}$	—	—	V
V_{IL}	Input LOW voltage	LVTTL	-0.3	—	0.8	V
		HSTL(DC) ^[43]	-0.3	—	$V_{REF} - 0.1$	V
		2.5 V LVCMOS	—	—	0.7	V
		1.8 V LVCMOS	—	—	$0.35 \times V_{DDIO}$	V

Notes

42. These parameters are met with V_{IM} disabled.

43. The DC specifications are measured under steady state conditions. The AC specifications are measured while switching at speed. AC V_{IH}/V_{IL} in HSTL mode are measured with 1 V/ns input edge rates.

44. HSTL Support and the corresponding tests support has been removed from the device from WW1830. No other functionality is impacted with this change

Electrical Characteristics *(continued)*

Over the Operating Range

Parameter	Description	Configuration	All Speed Bins			Unit
			Min	Typ	Max	
$\overline{\text{READY}}$ V_{OH}	Output HIGH voltage ($V_{DDIO} = \text{Min}$, $I_{OH} = -24 \text{ mA}$)	LVTTL	2.7 ^[45]	—	—	V
	($V_{DDIO} = \text{Min}$, $I_{OH} = -12 \text{ mA}$)	HSTL(DC) ^[46, 47]	$V_{DDIO} - 0.4$ ^[45]	—	—	V
	($V_{DDIO} = \text{Min}$, $I_{OH} = -12 \text{ mA}$)	HSTL (AC) ^[46, 47]	$V_{DDIO} - 0.5$ ^[45]	—	—	V
	($V_{DDIO} = \text{Min}$, $I_{OH} = -15 \text{ mA}$)	2.5 V LVCMOS	2.0 ^[45]	—	—	V
	($V_{DDIO} = \text{Min}$, $I_{OH} = -12 \text{ mA}$)	1.8 V LVCMOS	$V_{DDIO} - 0.45$ ^[45]	—	—	V
$\overline{\text{READY}}$ V_{OL}	Output HIGH voltage ($V_{DDIO} = \text{Min}$, $I_{OL} = 0.12 \text{ mA}$)	LVTTL	—	—	0.4 ^[45]	V
	($V_{DDIO} = \text{Min}$, $I_{OL} = 0.12 \text{ mA}$)	HSTL(DC) ^[46, 47]	—	—	0.4 ^[45]	V
	($V_{DDIO} = \text{Min}$, $I_{OL} = 0.12 \text{ mA}$)	HSTL (AC) ^[46, 47]	—	—	0.5 ^[45]	V
	($V_{DDIO} = \text{Min}$, $I_{OL} = 0.15 \text{ mA}$)	2.5 V LVCMOS	—	—	0.7 ^[45]	V
	($V_{DDIO} = \text{Min}$, $I_{OL} = 0.08 \text{ mA}$)	1.8 V LVCMOS	—	—	0.45 ^[45]	V
I_{OZ}	Output leakage current		–10	—	10	μA
I_{IX1}	Input leakage current except TDI, TMS, MRST, PORTSTD		–10	—	10	μA
I_{IX2}	Input leakage current TDI, TMS, MRST		–300	—	10	μA
I_{IX3}	Input leakage current PORTSTD		–10	—	300	μA

Notes

45. These parameters are met with V_{IM} disabled.

46. The DC specifications are measured under steady state conditions. The AC specifications are measured while switching at speed. AC V_{IH}/V_{IL} in HSTL mode are measured with 1 V/ns input edge rates.

47. HSTL Support and the corresponding tests support has been removed from the device from WW1830. No other functionality is impacted with this change

Electrical Characteristics

Over the Operating Range

Parameter	Description	Configuration		-200		-167		Unit
				Typ	Max	Typ	Max	
I_{CC}	Operating current ($V_{CORE} = \text{Max}$, $I_{OUT} = 0 \text{ mA}$) outputs disabled	512K × 72	Commercial	1440	1800	1280	1620	mA
			Industrial	–	–	1330	1730	mA
		1024K × 36	Commercial	1180	1500	1050	1350	mA
			Industrial	–	–	1110	1470	mA
		2048K × 18	Commercial	1130	1430	1000	1290	mA
			Industrial	–	–	1060	1410	mA
		256K × 72	Commercial	800	980	700	880	mA
			Industrial	820	1030	730	930	mA
		512K × 36	Commercial	640	800	570	720	mA
			Industrial	670	860	590	780	mA
		1024K × 18	Commercial	610	770	540	690	mA
			Industrial	640	830	570	750	mA
		128K × 72	Commercial	640	790	560	700	mA
			Industrial	660	830	580	740	mA
		256K × 36	Commercial	540	640	470	570	mA
			Industrial	550	670	490	600	mA
		512K × 18	Commercial	550	660	480	580	mA
			Industrial	570	690	500	610	mA
		64K × 36	Commercial	–	–	–	–	mA
			Industrial	–	–	–	–	mA
I_{SB1}	Standby current (both ports TTL Level) CE_L and $CE_R \geq V_{IH}$, $f = f_{MAX}$	512K × 72	Commercial	1000	1250	920	1160	mA
			Industrial	–	–	970	1260	mA
		1024K × 36	Commercial	910	1140	820	1050	mA
			Industrial	–	–	880	1160	mA
		2048K × 18	Commercial	890	1110	810	1030	mA
			Industrial	–	–	860	1140	mA
		256K × 72	Commercial	500	630	460	580	mA
			Industrial	530	680	490	630	mA
		512K × 36	Commercial	460	570	410	530	mA
			Industrial	480	630	440	580	mA
		1024K × 18	Commercial	450	560	410	520	mA
			Industrial	470	610	430	570	mA
		128K × 72	Commercial	400	490	360	450	mA
			Industrial	420	540	380	490	mA
		256K × 36	Commercial	380	440	340	400	mA
			Industrial	390	470	360	430	mA
		512K × 18	Commercial	390	460	350	410	mA
			Industrial	410	480	370	440	mA
		64K × 36	Commercial	–	–	–	–	mA
			Industrial	–	–	–	–	mA

Electrical Characteristics *(continued)*

Over the Operating Range

Parameter	Description	Configuration		-200		-167		Unit
				Typ	Max	Typ	Max	
I_{SB2}	Standby current (one port TTL or CMOS level) $\overline{CE}_L \mid \overline{CE}_R \geq V_{IH}, f = f_{MAX}$	512K × 72	Commercial	1300	1570	1160	1410	mA
			Industrial	–	–	1210	1520	mA
		1024K × 36	Commercial	1090	1330	980	1210	mA
			Industrial	–	–	1030	1330	mA
		2048K × 18	Commercial	1040	1270	930	1160	mA
			Industrial	–	–	980	1270	mA
		256K × 72	Commercial	650	790	580	710	mA
			Industrial	680	840	610	760	mA
		512K × 36	Commercial	550	670	490	610	mA
			Industrial	570	730	520	670	mA
		1024K × 18	Commercial	520	640	470	580	mA
			Industrial	550	690	490	640	mA
		128K × 72	Commercial	520	630	460	560	mA
			Industrial	550	670	480	610	mA
		256K × 36	Commercial	460	530	400	470	mA
			Industrial	480	560	430	500	mA
		512K × 18	Commercial	460	530	410	480	mA
			Industrial	480	560	430	510	mA
		64K × 36	Commercial	–	–	–	–	mA
			Industrial	–	–	–	–	mA

Electrical Characteristics

Over the Operating Range

Parameter	Description	Configuration		All Speed Bins		Unit
				Typ	Max	
I_{SB3}	Standby current (both ports CMOS level) $\overline{CE}_L$ and $\overline{CE}_R \geq V_{CORE} - 0.2$ V, $f = 0$	512K × 72	Commercial	410	590	mA
			Industrial	460	700	mA
		1024K × 36	Commercial	410	590	mA
			Industrial	460	700	mA
		2048K × 18	Commercial	410	590	mA
			Industrial	460	700	mA
		256K × 72	Commercial	210	300	mA
			Industrial	230	350	mA
		512K × 36	Commercial	210	300	mA
			Industrial	230	350	mA
		1024K × 18	Commercial	210	300	mA
			Industrial	230	350	mA
		128K × 72	Commercial	150	200	mA
			Industrial	170	220	mA
		256K × 36	Commercial	150	200	mA
			Industrial	170	220	mA
		512K × 18	Commercial	150	200	mA
			Industrial	170	220	mA

Capacitance

Signals	Packages			
	CYD18S72V18 ^[54] CYD09S72V18 CYD18S36V18 CYD09S36V18 CYD02S36V18	CYD18S18V18 CYD09S18V18	CYD36S72V18 CYD36S36V18	CYD36S18V18
$\overline{OE}$	12 pF	12 pF	20 pF	20 pF
$\overline{BE}$, DQ	10 pF	18 pF	16 pF	30 pF
All other signals	10 pF	10 pF	16 pF	16 pF

Thermal Resistance

Parameter	Description	Test Conditions	484-ball BGA	256-ball BGA (18 Mbit only)	256-ball BGA (9 Mbit & 2 Mbit)	Unit
θ_{JA}	Thermal resistance (junction to ambient)	Still air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	14.92	17.02	18.31	°C/W
θ_{JC}	Thermal resistance (junction to case)		3.6	1.25	1.68	°C/W

AC Test Load and Waveforms

Figure 9. Output Test Load for LVTTTL/CMOS

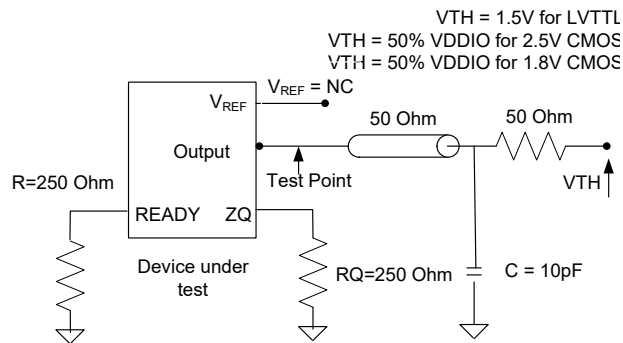


Figure 10. Output Test Load for HSTL^[54]

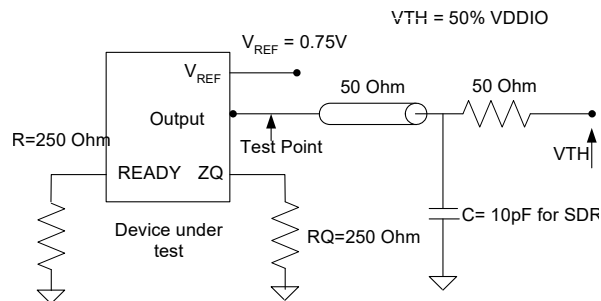
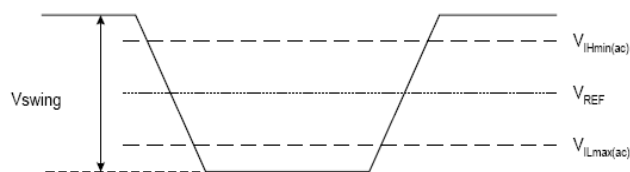


Figure 11. HSTL Input Waveform^[54]

AC Input Test Signal Waveform



$$V_{swing} = 1.0V$$

$$V_{REF} = 0.75V$$

$$V_{IH} = 1.25V$$

$$V_{IL} = 0.25V$$

$$\text{Slew} = 2.0V/ns$$

All input parameters are referenced to V_{REF}

Switching Characteristics

Over the Operating Range

Table 12. SDR Mode, Signals Affected by DLL

Parameter	Description	DLL ON (LOWSPD=1) ^[50]				DLL OFF (LOWSPD=0) ^[50]		Unit
		−200		−167				
		Min	Max	Min	Max	Min	Max	
t _{CD2} ^[53]	C rise to DQ valid for pipelined mode	−	3.30 ^[49, 52]	−	4.00 ^[49, 52]	−	6.00 ^[49, 52]	ns
t _{CCQ} ^[53]	C rise to CQ rise	1.00	3.30 ^[52]	1.00	4.00 ^[52]	1.00	6.00 ^[52]	ns
t _{CKHZ2} ^[48, 53]	C rise to DQ output high Z in pipelined mode	1.00	3.30 ^[49, 52]	1.00	4.00 ^[49, 52]	1.00	6.00 ^[49, 52]	ns
t _{CKLZ2} ^[48, 53]	C rise to DQ output low Z in pipelined mode	1.00	−	1.00	−	1.00	−	ns

Table 13. SDR Mode

Parameter	Description		-200		-167		Unit
			Min	Max	Min	Max	
f _{MAX} (PIPELINED)	Maximum operating frequency for pipelined mode		100	200	100	167	MHz
f _{MAX} (FLOW THROUGH)	Maximum operating frequency for flow through mode		–	77	–	66.7	MHz
t _{CYC} (PIPELINED)	C clock cycle time for pipelined mode		5.00 ^[52]	10.00	6.00 ^[52]	10.00	ns
t _{CYC} (FLOW THROUGH)	C clock cycle time for flow through mode		13.00 ^[52]	–	15.00 ^[52]	–	ns
t _{CKD}	C clock duty time		45	55	45	55	%
t _{SD}	Data input setup time to C rise	HSTL	1.50 ^[49, 52]	–	1.70 ^[49, 52]	–	ns
		1.8 V LVCMOS					
		2.5 V LVCMOS 3.3 V LVTTTL	1.75 ^[49, 52]	–	1.95 ^[49, 52]		ns
t _{HD} ^[51]	Data input hold time after C rise		0.5	–	0.5	–	ns
t _{SAC}	Address and control input setup time to C rise	HSTL ^[54]	1.50 ^[49, 51, 52]	–	1.70 ^[49, 51, 52]	–	ns
		1.8 V L VCMOS					
		2.5 V LVCMOS 3.3 V LVTTTL	1.75 ^[49, 51, 52]	–	1.95 ^[49, 51, 52]	–	ns
t _{HAC} ^[51]	Address and control input hold time after C rise		0.50	–	0.60	–	ns
t _{OE}	Output enable to data valid		–	4.40 ^[49, 52]	–	5.00 ^[49, 52]	ns
t _{OLZ} ^[48]	OE to low Z		1.00	–	1.00	–	ns

Notes

48. Parameters specified with the load capacitance in Figure 9 on page 24 and Figure 10 on page 24.

49. For the x18 devices, add 200 ps to this parameter in Table 13.

50. Test conditions assume a signal transition time of 2 V/ns.

51. Add 300 ps to this timing for 36M devices.

52. Add 15% to this parameter if a V_{CORE} of 1.5 V is used.

53. This parameter assumes input clock cycle to cycle jitter of ± 0 ps.

54. HSTL Support and the corresponding tests support has been removed from the device from WW1830. No other functionality is impacted with this change

Table 13. SDR Mode (continued)

Parameter	Description	-200		-167		Unit
		Min	Max	Min	Max	
$t_{OHZ}^{[55]}$	OE to high Z	1.00	4.40 ^[56, 57]	1.00	5.00 ^[56, 57]	ns
t_{CD1}	C rise to DQ valid for flow through mode (LowSPD = 0)	–	9.00 ^[56, 57]	–	11.00 ^[56, 57]	ns
t_{CA1}	C rise to address readback valid for flow through mode	–	9.00 ^[57]	–	11.00 ^[57]	ns
t_{CA2}	C rise to address readback valid for pipelined mode	–	5.00 ^[57]	–	6.00 ^[57]	ns
$t_{DC}^{[58]}$	DQ output hold after C rise	1.00	–	1.00	–	ns
t_{JIT}	Clock input cycle to cycle jitter	–	±200	–	±200	ps
$t_{CQHCV}^{[58]}$	Echo clock (CQ) high to output valid	HSTL ^[59] 1.8 V LVCMOS		–	0.70 ^[56]	ns
		2.5 V LVCMOS 3.3 V LVTTTL		–	0.80 ^[56]	ns
$t_{CQHCV}^{[58]}$	Echo clock (CQ) high to output hold	HSTL ^[59] 1.8 V LVCMOS		–0.70	–	ns
		2.5 V LVCMOS 3.3 V LVTTTL		–0.85	–	ns
$t_{CKHZ1}^{[55]}$	C rise to DQ output high Z in flow through mode	1.00	9.00 ^[56, 57]	1.00	11.00 ^[56, 57]	ns
$t_{CKLZ1}^{[55]}$	C rise to DQ output low Z in flow through mode	1.00	–	1.00	–	ns
t_{AC}	Address output hold after C rise	1.00	–	1.00	–	ns
$t_{CKHZA1}^{[55]}$	C rise to address output high Z for flow through mode	1.00	9.00 ^[57]	1.00	11.00 ^[57]	ns
$t_{CKHZA2}^{[55]}$	C rise to address output high Z for pipelined mode	1.00	5.00 ^[57]	1.00	6.00 ^[57]	ns
$t_{CKLZA}^{[55]}$	C rise to address output low Z	1.00	–	1.00	–	ns
t_{SCINT}	C rise to $\overline{CNTINT}$ low	1.00	3.30 ^[57]	1.00	4.00 ^[57]	ns
t_{RCINT}	C rise to $\overline{CNTINT}$ high	1.00	3.30 ^[57]	1.00	4.00 ^[57]	ns
t_{SINT}	C rise to $\overline{INT}$ low	0.50	7.00 ^[57]	0.50	8.00 ^[57]	ns
t_{RINT}	C rise to $\overline{INT}$ high	0.50	7.00 ^[57]	0.50	8.00 ^[57]	ns
t_{BSY}	C rise to $\overline{BUSY}$ valid	1.00	3.30 ^[57]	1.00	4.00 ^[57]	ns

Notes

55. Parameters specified with the load capacitance in Figure 9 on page 24 and Figure 10 on page 24.

56. For the × 18 devices, add 200 ps to this parameter in Table 13.

57. Add 15% to this parameter if a V_{CORE} of 1.5 V is used.

58. This parameter assumes input clock cycle-to-cycle jitter of ±0 ps.

59. HSTL Support and the corresponding tests support has been removed from the device from WW1830. No other functionality is impacted with this change

Table 14. Master Reset Timing

Parameter	Description	–200		–167		Unit
		Min	Max	Min	Max	
t_{PUP}	Power-up time	1	–	1	–	ms
t_{RS}	Master reset pulse width	5	–	5	–	cycles
t_{RSR}	Master reset recovery time	5	–	5	–	cycles
t_{RSF}	Master reset to outputs inactive/Hi Z	–	15	–	18	ns
$t_{RDY}^{[60]}$	Master reset release to port ready	–	1024	–	1024	cycles
$t_{CORDY}^{[61]}$	C rise to port ready	–	9.5 ^[62]	–	11 ^[62]	ns

Table 15. JTAG Timing

Parameter	Description	–200		–167		Unit
		Min	Max	Min	Max	
f_{JTAG}	JTAG TAP controller frequency	–	20	–	20	MHz
t_{TCYC}	TCK cycle time	50	–	50	–	ns
t_{TH}	TCK high time	20	–	20	–	ns
t_{TL}	TCK low time	20	–	20	–	ns
t_{TMSS}	TMS setup to TCK rise	10	–	10	–	ns
t_{TMSH}	TMS hold to TCK rise	10	–	10	–	ns
t_{TDIS}	TDI setup to TCK rise	10	–	10	–	ns
t_{TDIH}	TDI hold to TCK rise	10	–	10	–	ns
t_{TDOV}	TCK low to TDO valid	–	10	–	10	ns
t_{TDOX}	TCK low to TDO invalid	0	–	0	–	ns
t_{JXZ}	TCK low to TDO high Z	–	15	–	15	ns
t_{JZX}	TCK low to TDO active	–	15	–	15	ns
t_{JZX}	TCK low to TDO active	–	15	–	15	ns

Notes

60. READY is a wired OR capable output with a weak pull-down. For a decreased falling delay, connect a 250-Ω resistor to V_{SS}.

61. Add this propagation delay after t_{RDY} for all Master Reset Operations.

62. Add 15% to this parameter if a V_{CORE} of 1.5 V is used.

Switching Waveforms

Figure 12. JTAG Timing

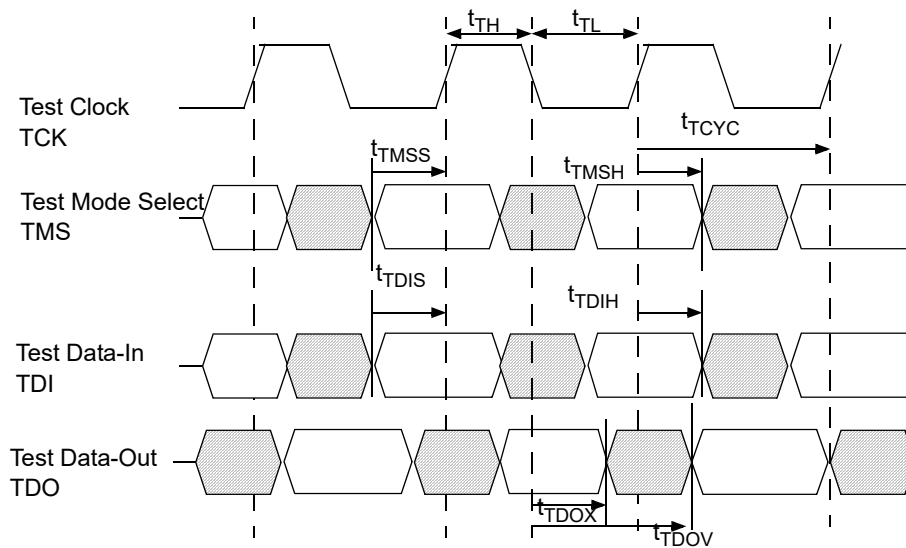
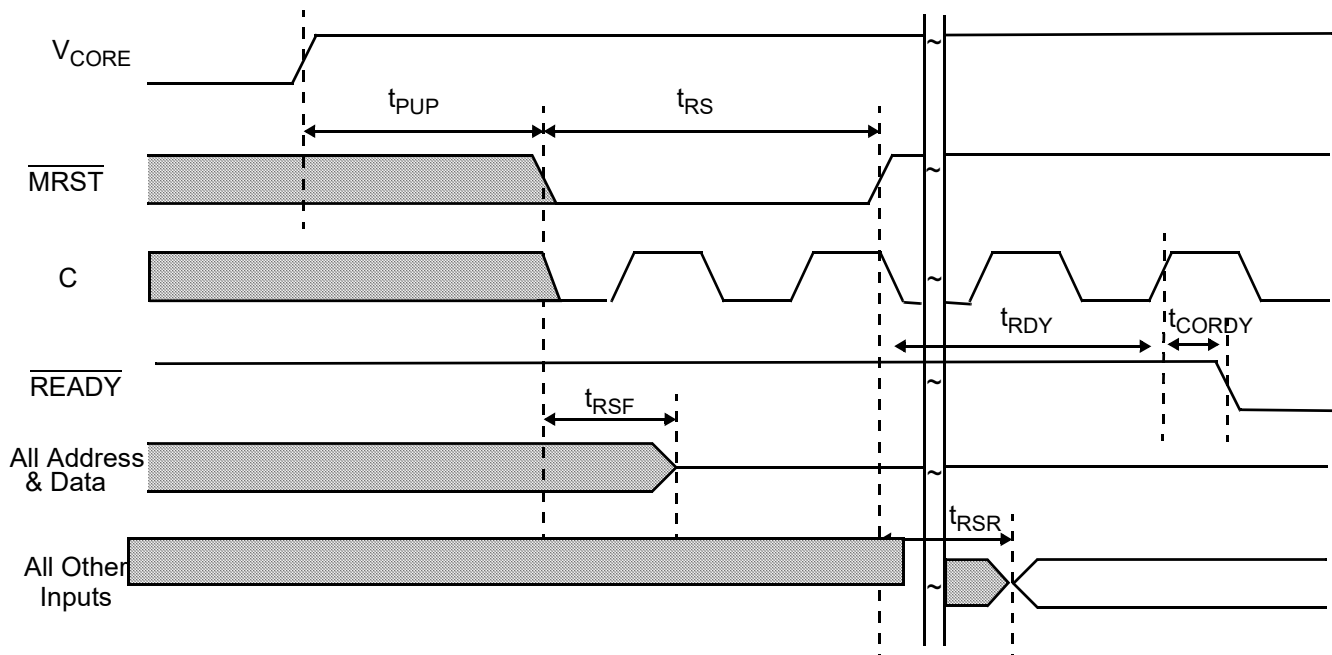


Figure 13. Master Reset ^[63]



Note

63. $\overline{READY}$ is a wired OR capable output with a weak pull-down. For a decreased falling delay, connect a 250- Ω resistor to V_{SS} .

Switching Waveforms (continued)

Figure 14. READ Cycle for Pipelined Mode

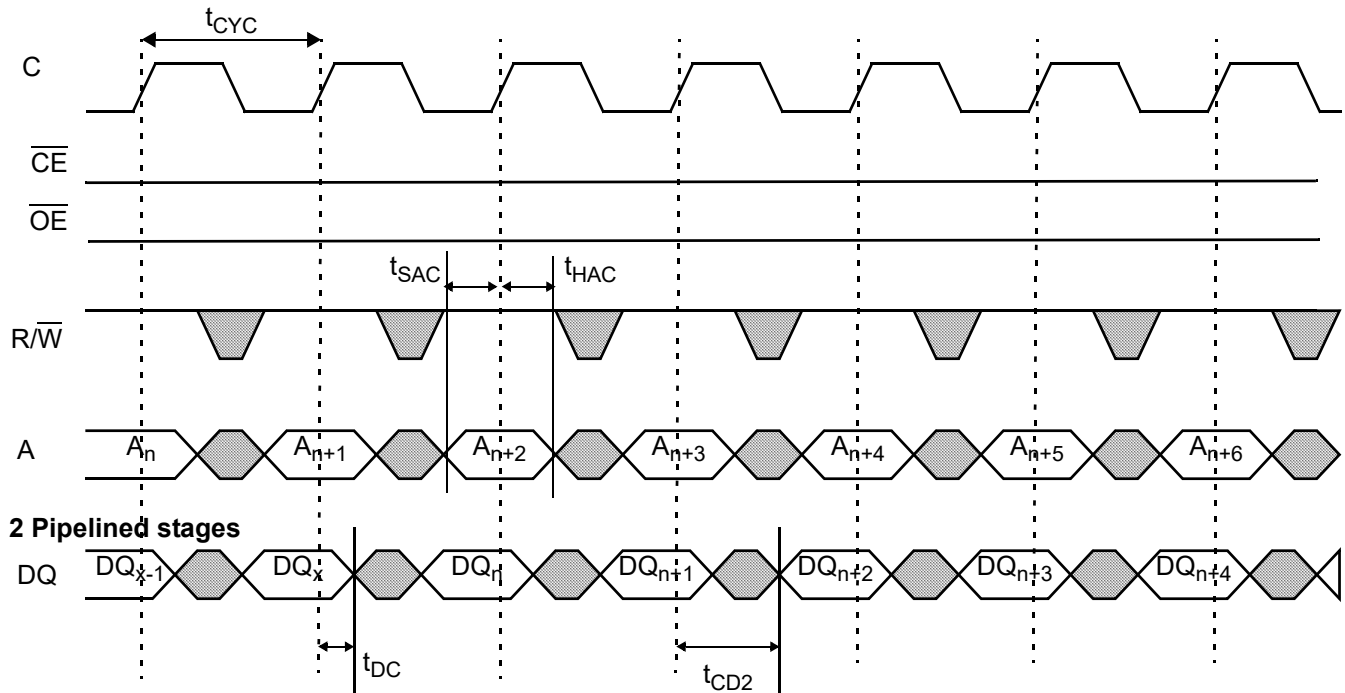
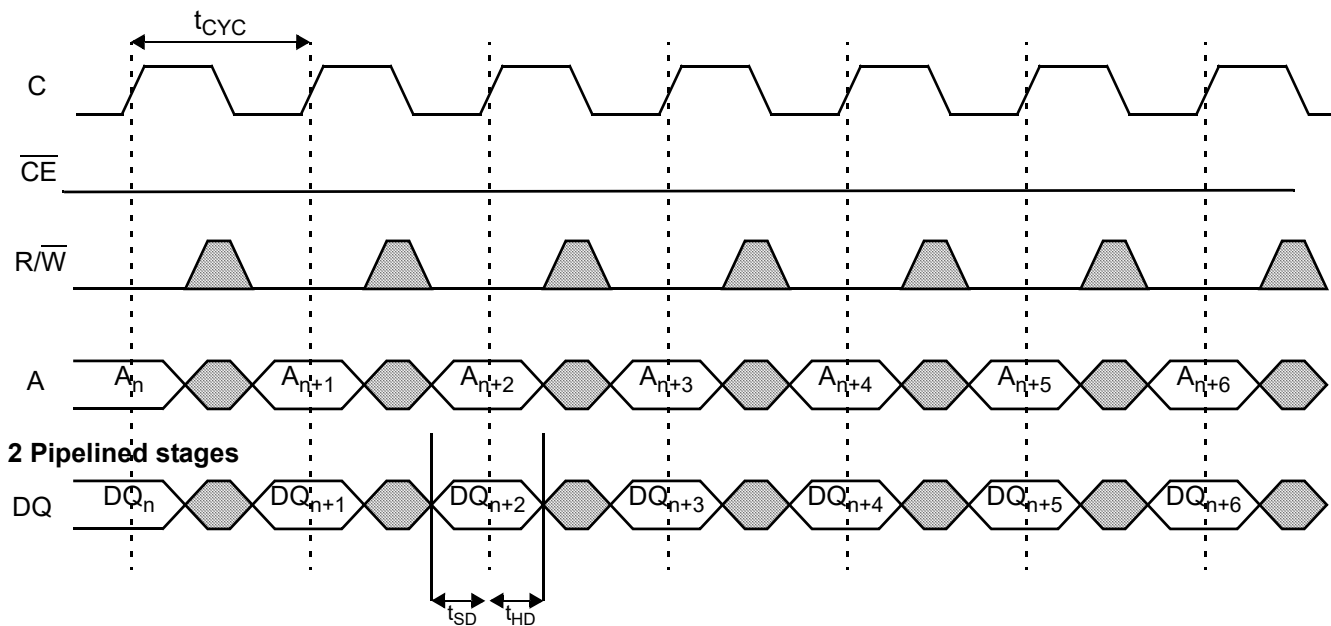


Figure 15. WRITE Cycle for Pipelined and Flow through Modes



Switching Waveforms (continued)

Figure 16. READ with Address Counter Advance for Pipelined Mode

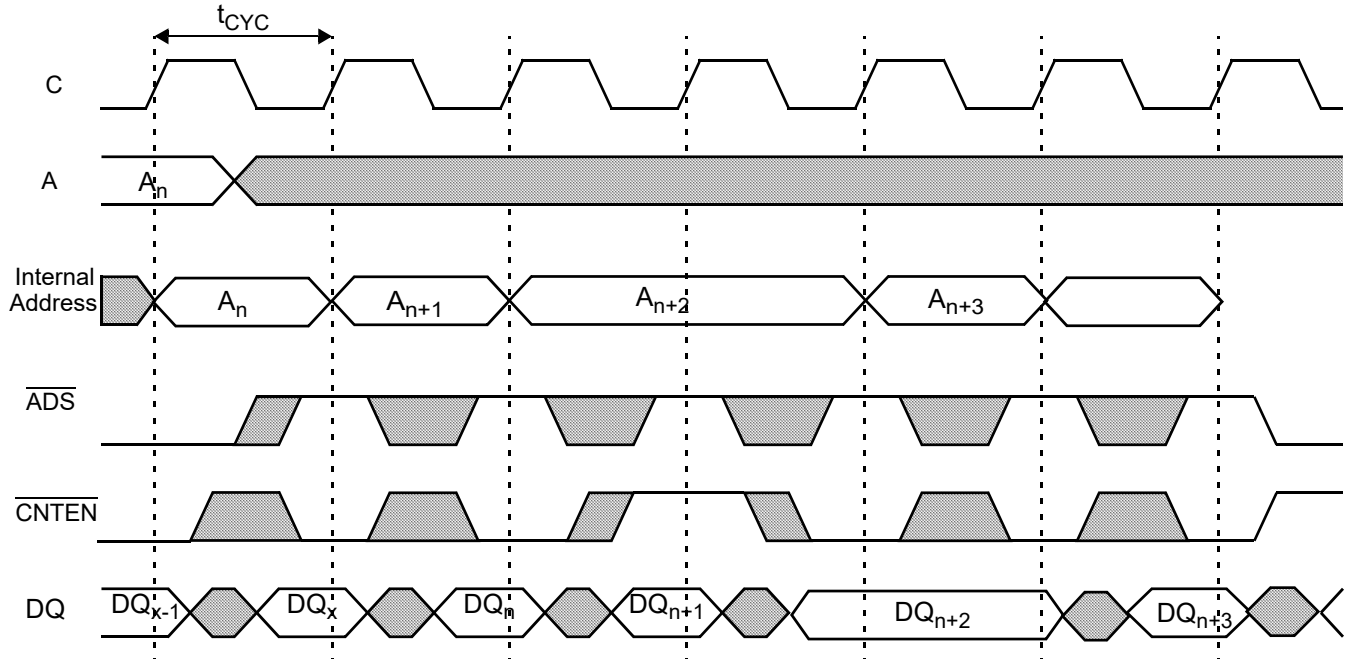
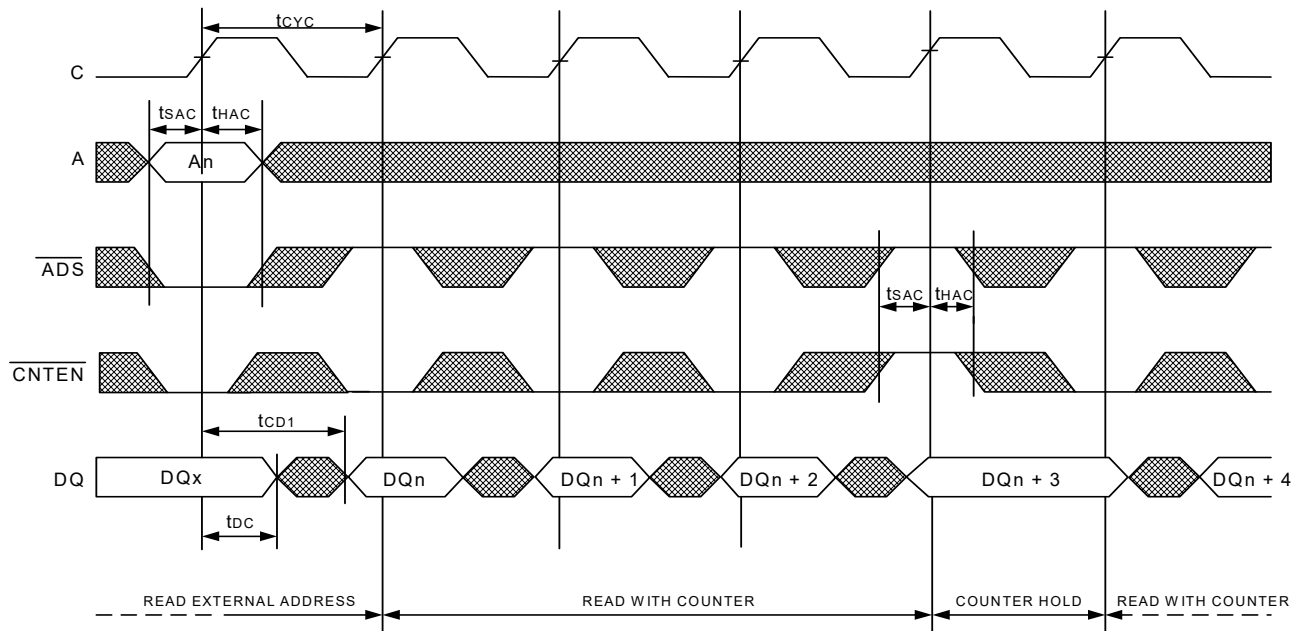


Figure 17. READ with Address Counter Advance for Flow through Mode



Switching Waveforms (continued)

Figure 18. Port-to-Port WRITE-READ for Pipelined Mode

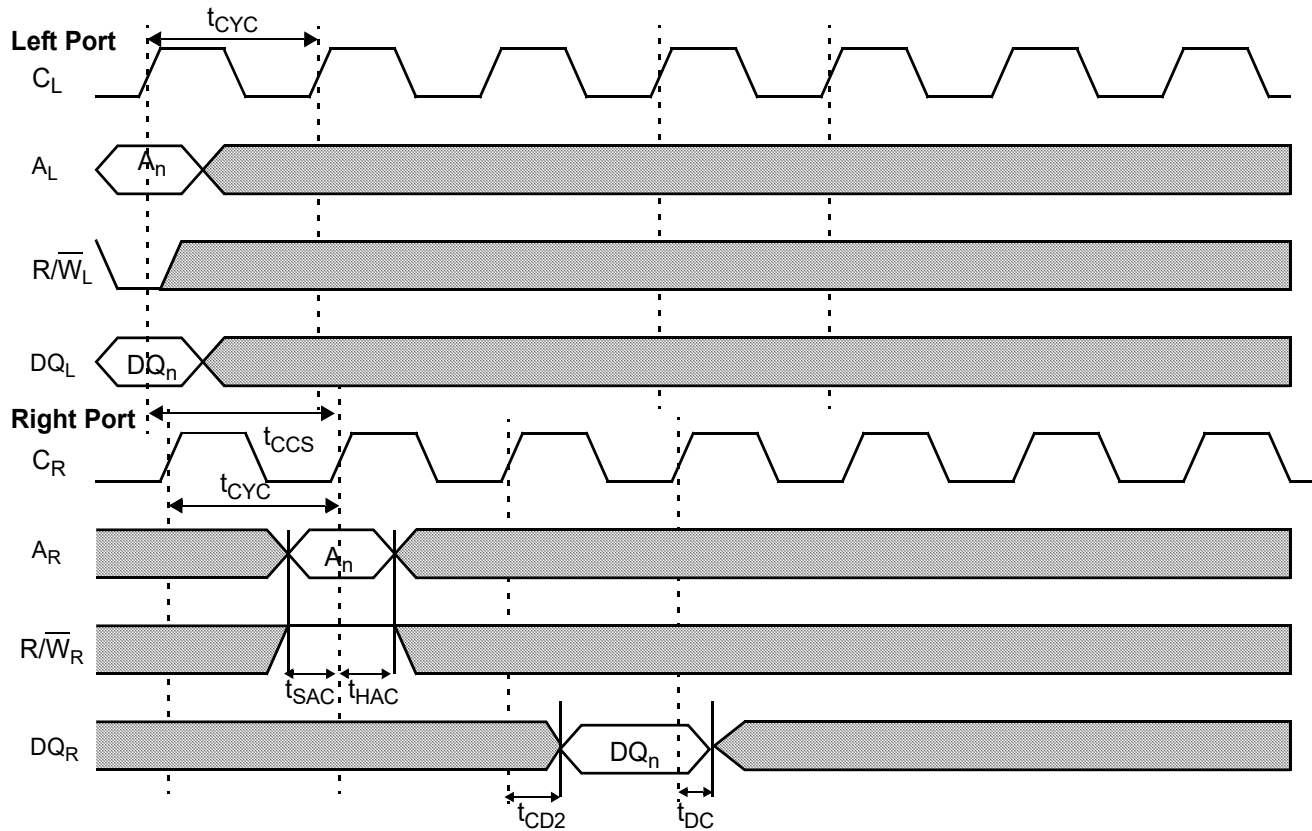
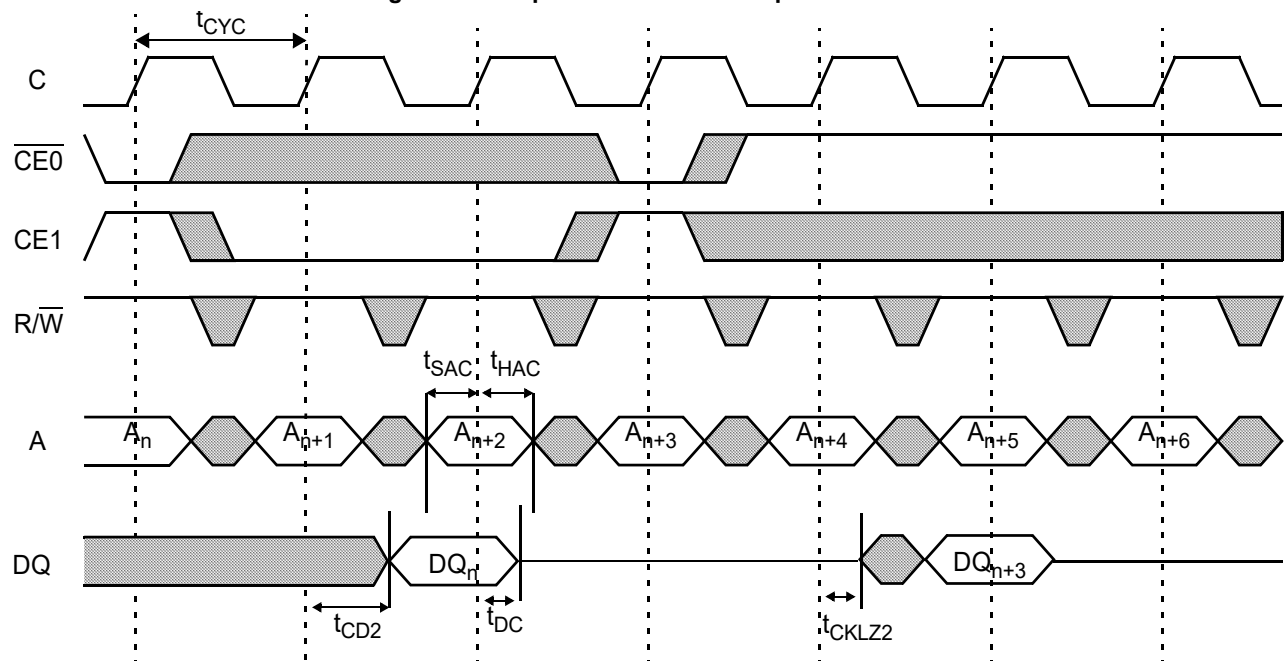


Figure 19. Chip Enable READ for Pipelined Mode



Switching Waveforms (continued)

Figure 20. OE Controlled WRITE for Pipelined Mode

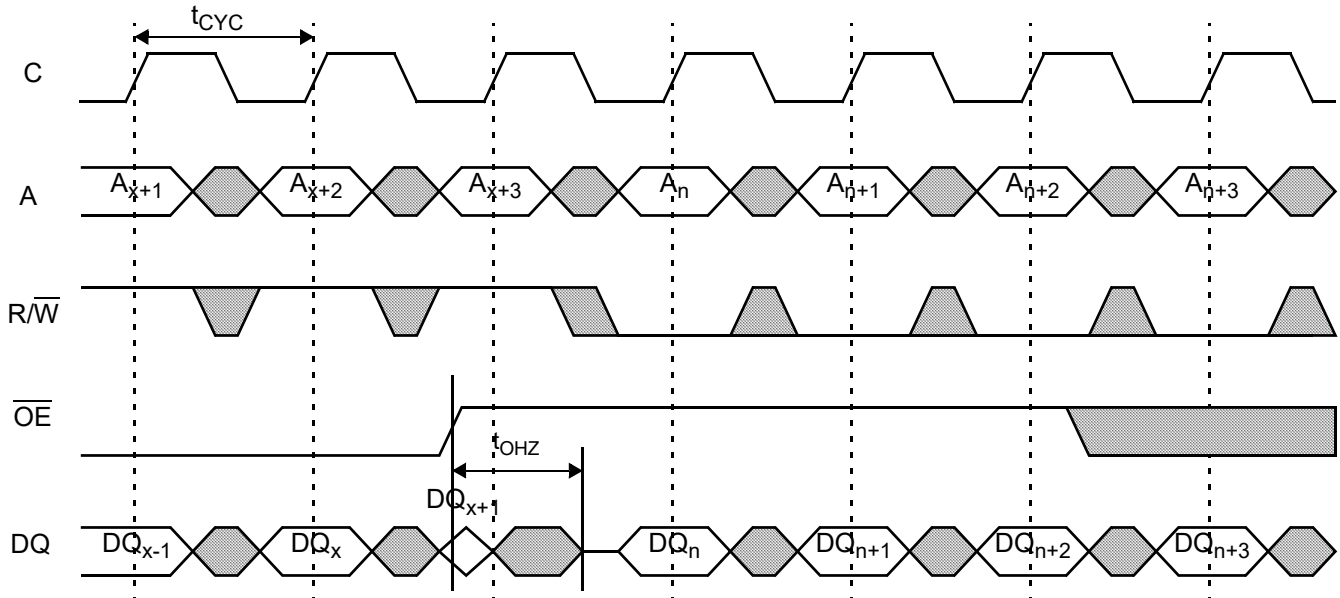
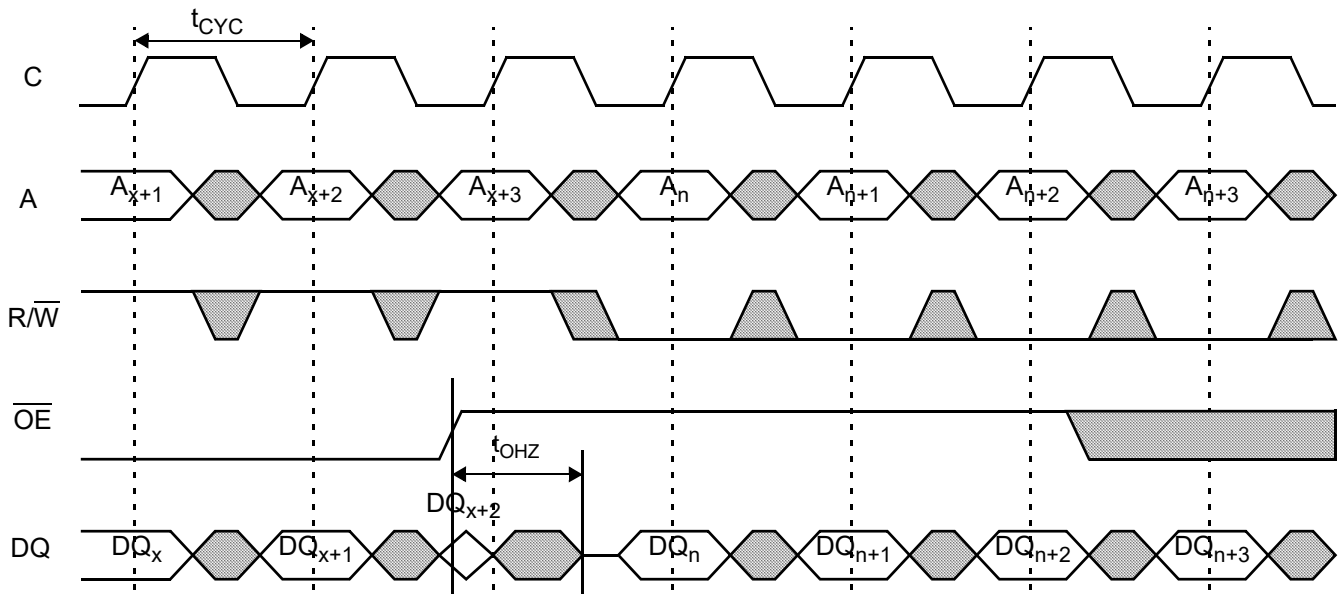
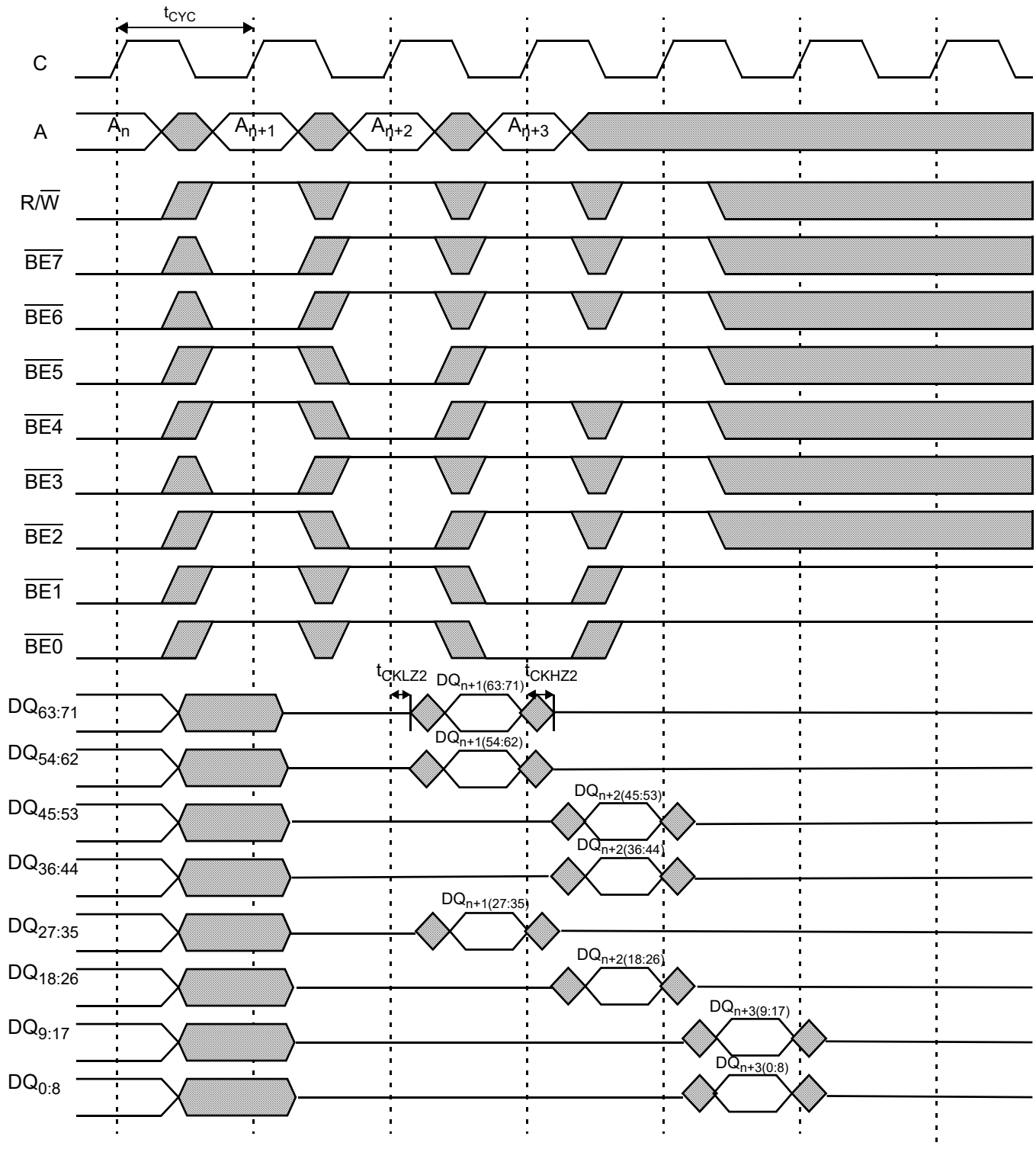


Figure 21. OE Controlled WRITE for Flow through Mode



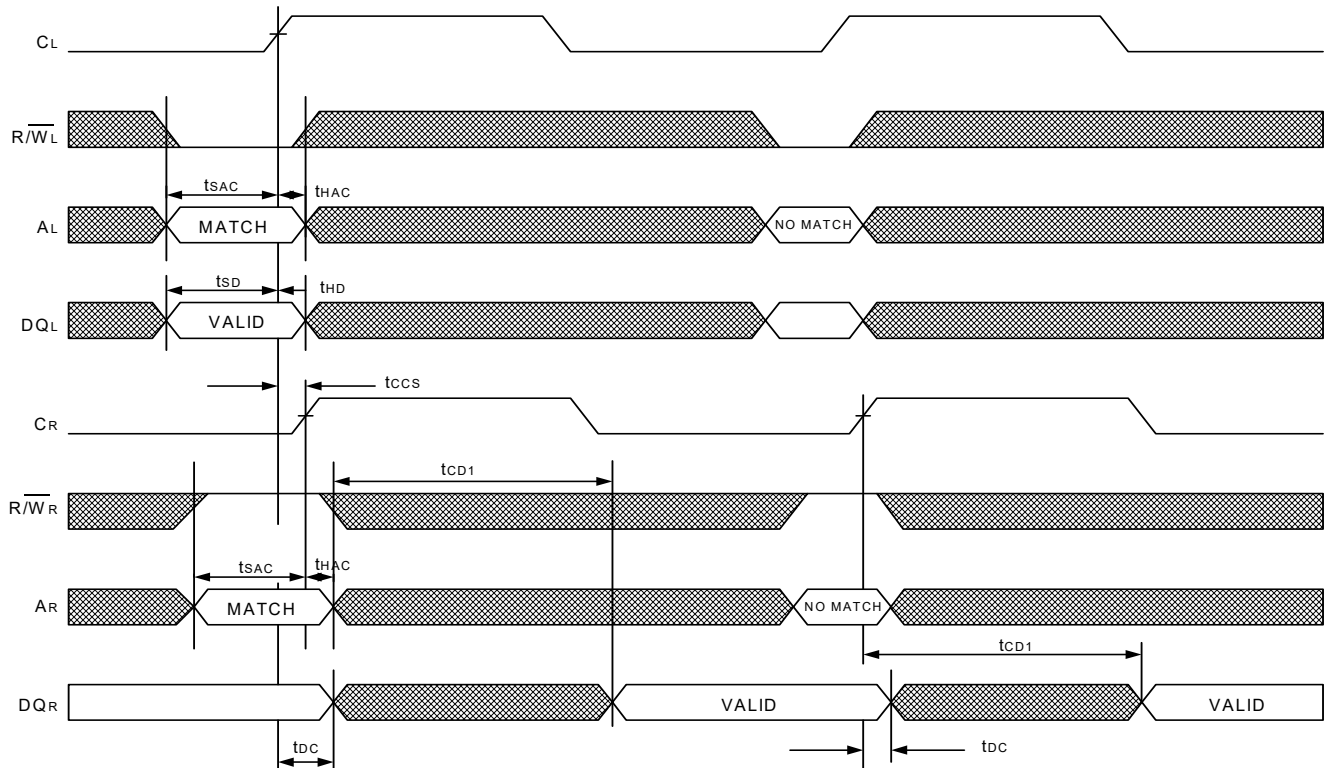
Switching Waveforms (continued)

Figure 22. Byte-Enable READ for Pipelined Mode



Switching Waveforms *(continued)*

Figure 23. Port-to-Port WRITE-to-READ for Flow through Mode



Switching Waveforms (continued)

Figure 24. Busy Address Readback for Pipelined and Flow through Modes, $\overline{\text{CNT}}/\overline{\text{MSK}} = \overline{\text{RET}} = \text{LOW}$ [64]

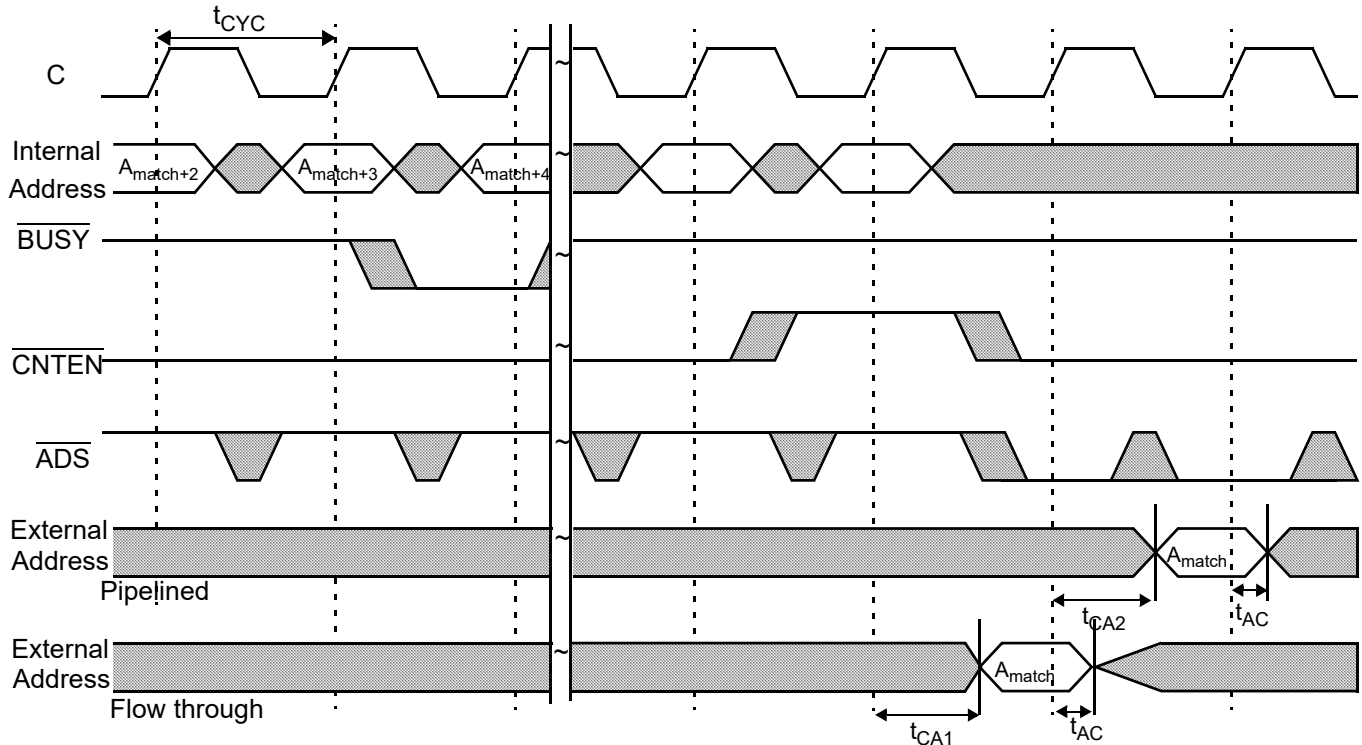
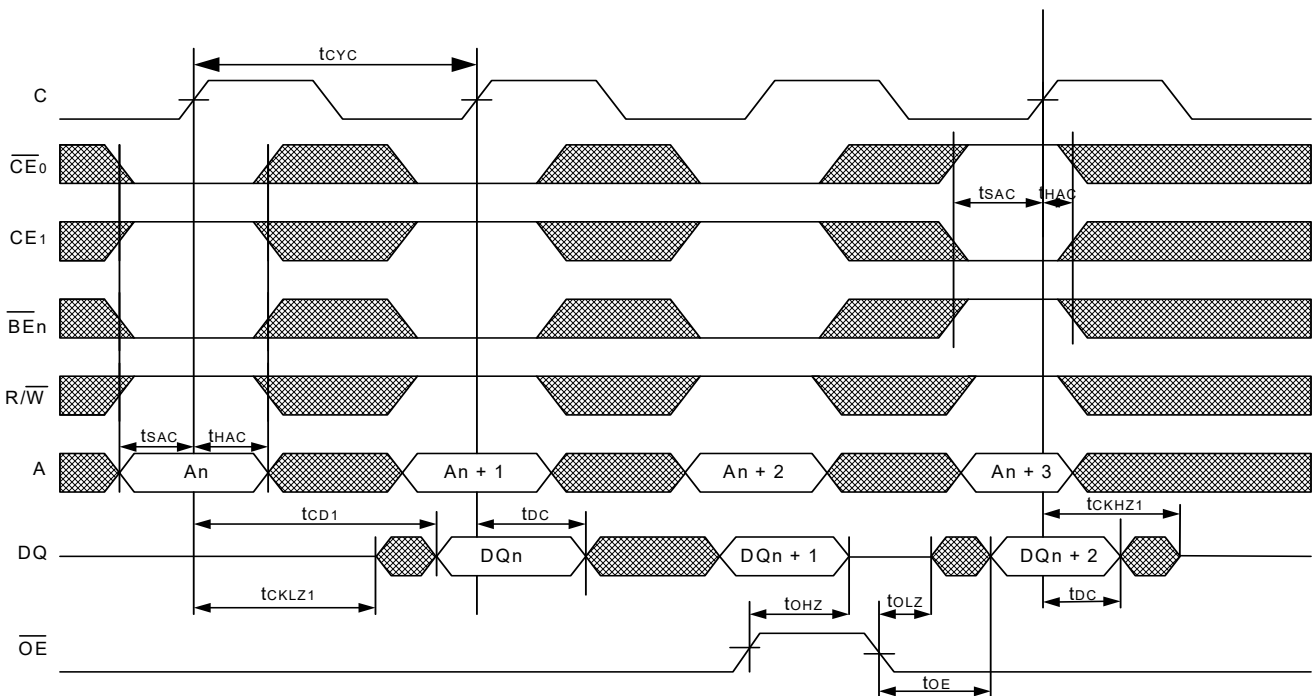


Figure 25. Read Cycle for Flow through Mode



Note

64. A_{match} is the matching address that is reported on the address bus of the losing port. The counter operation selected for reporting the address is "Busy Address Readback."

Switching Waveforms (continued)

Figure 26. READ-to-WRITE for Pipelined Mode ($\overline{OE} = V_{IL}$) [65, 66, 67]

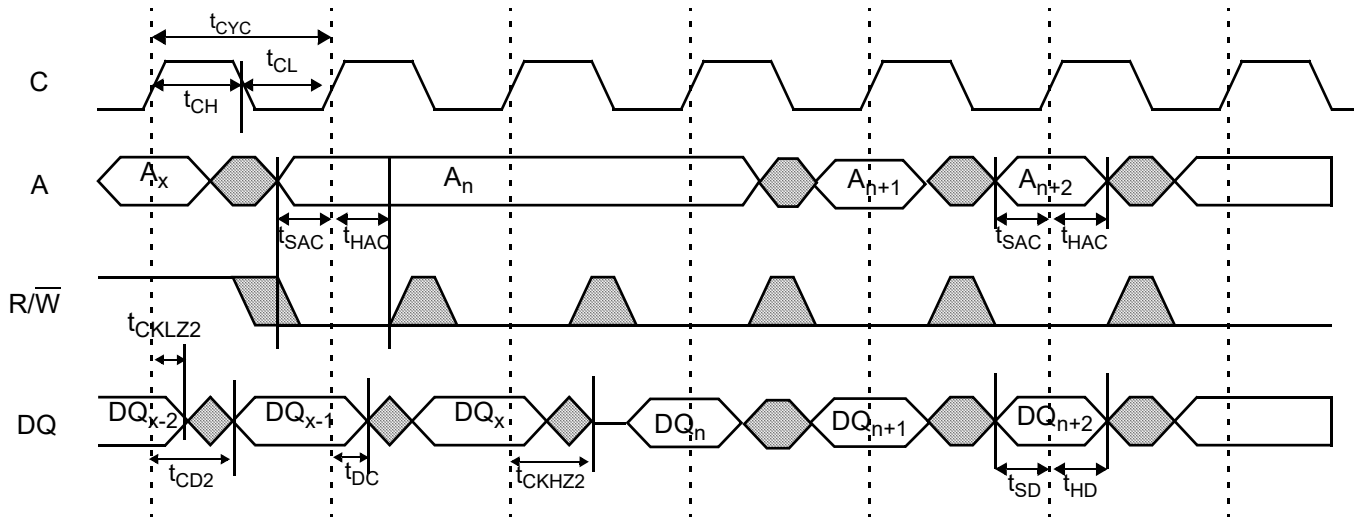
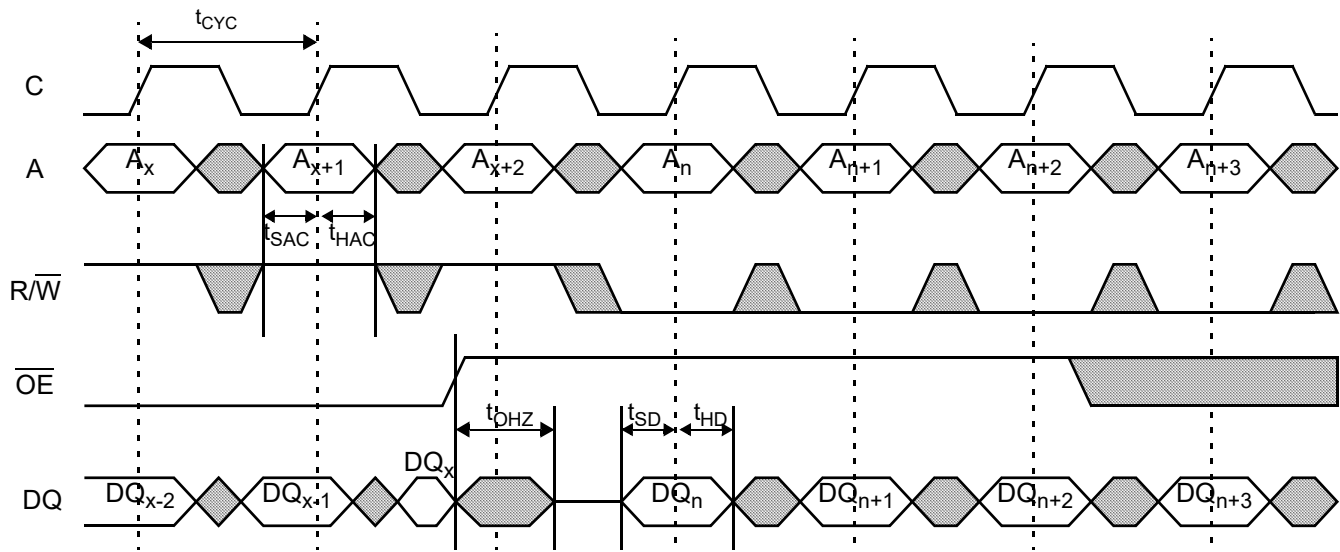


Figure 27. READ-to-WRITE for Pipelined Mode ($\overline{OE}$ Controlled) [68, 69]



Notes

65. When $\overline{OE} = V_{IL}$, the last read operation is enabled to complete before the DQ bus is tristated and the user is enabled to drive write data.

66. Two dummy writes are issued to accomplish bus turnaround. The third instruction is the first valid write.

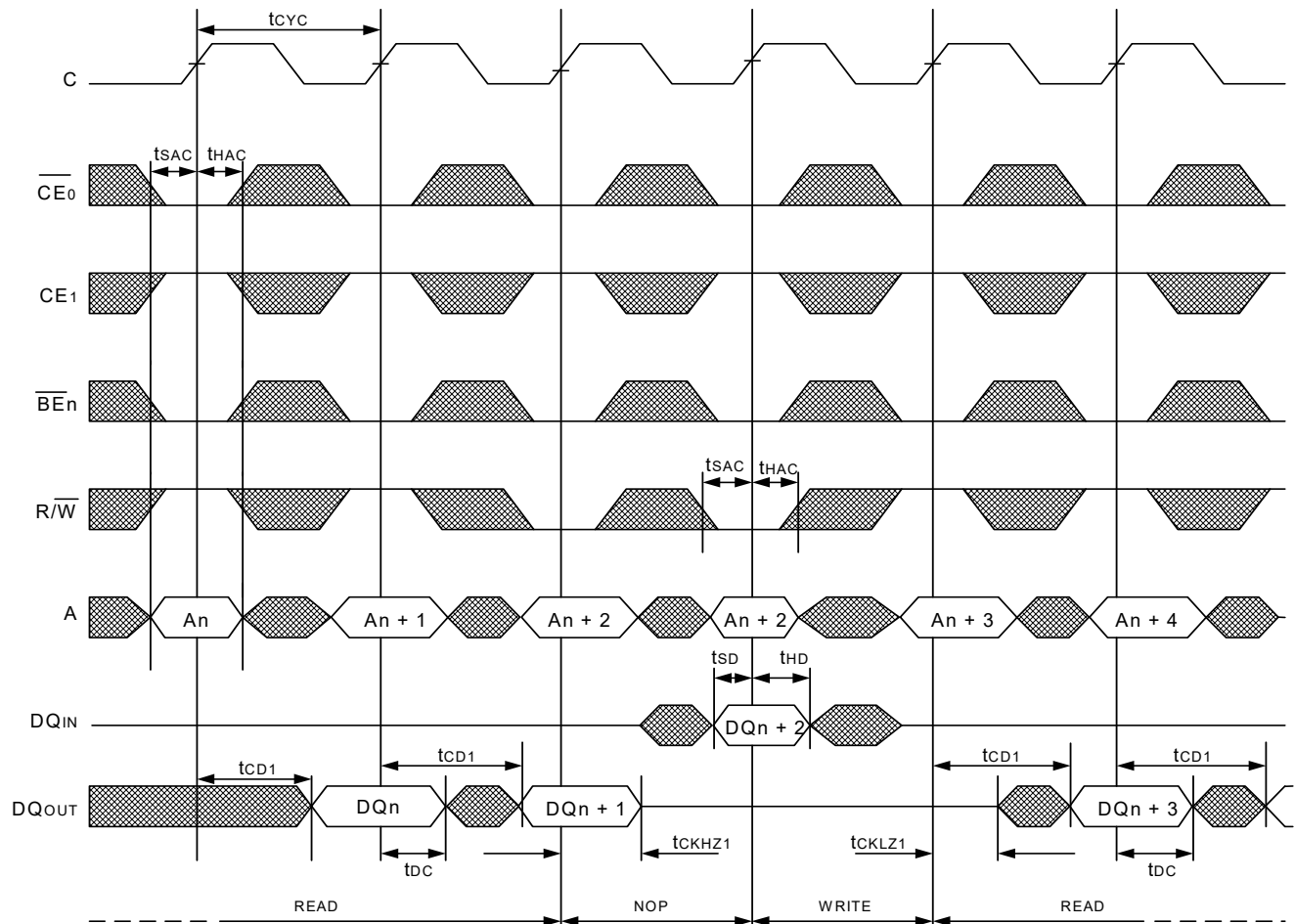
67. Chip enable or all byte enables are held inactive during the two dummy writes to avoid data corruption.

68. $\overline{OE}$ is deasserted and t_{OHZ} enabled to elapse before the first write operation is issued.

69. Any write scheduled to complete after $\overline{OE}$ is deasserted is pre-empted.

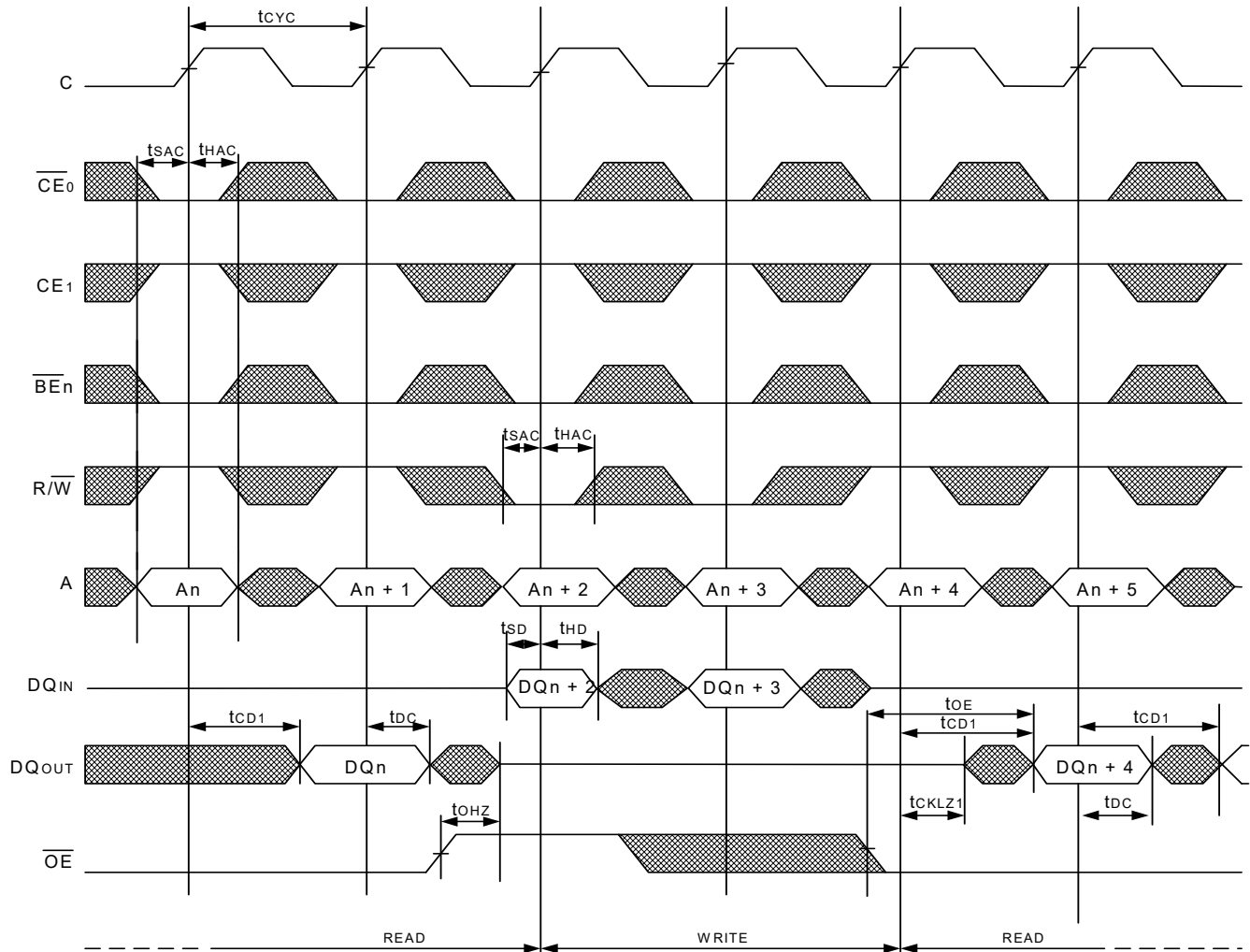
Switching Waveforms (continued)

Figure 28. Read-to-Write-to-Read for Flow through Mode ($\overline{OE} = \text{LOW}$)



Switching Waveforms (continued)

Figure 29. Read-to-Write-to-Read for Flow through Mode ($\overline{OE}$ Controlled)



Switching Waveforms (continued)

Figure 30. BUSY Timing, WRITE-WRITE Collision for Pipelined and Flow through Modes, Clock Timing Violates t_{CCS} . (Flag Both Ports)

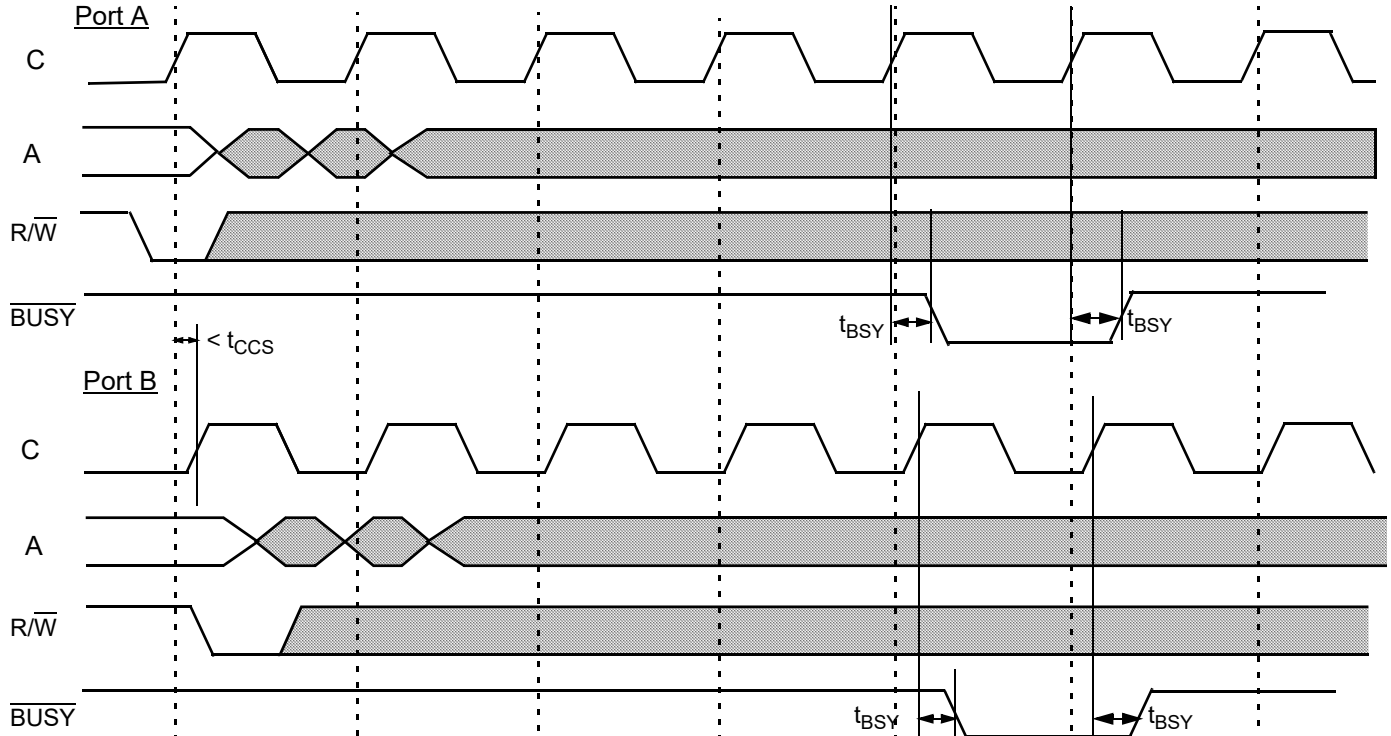
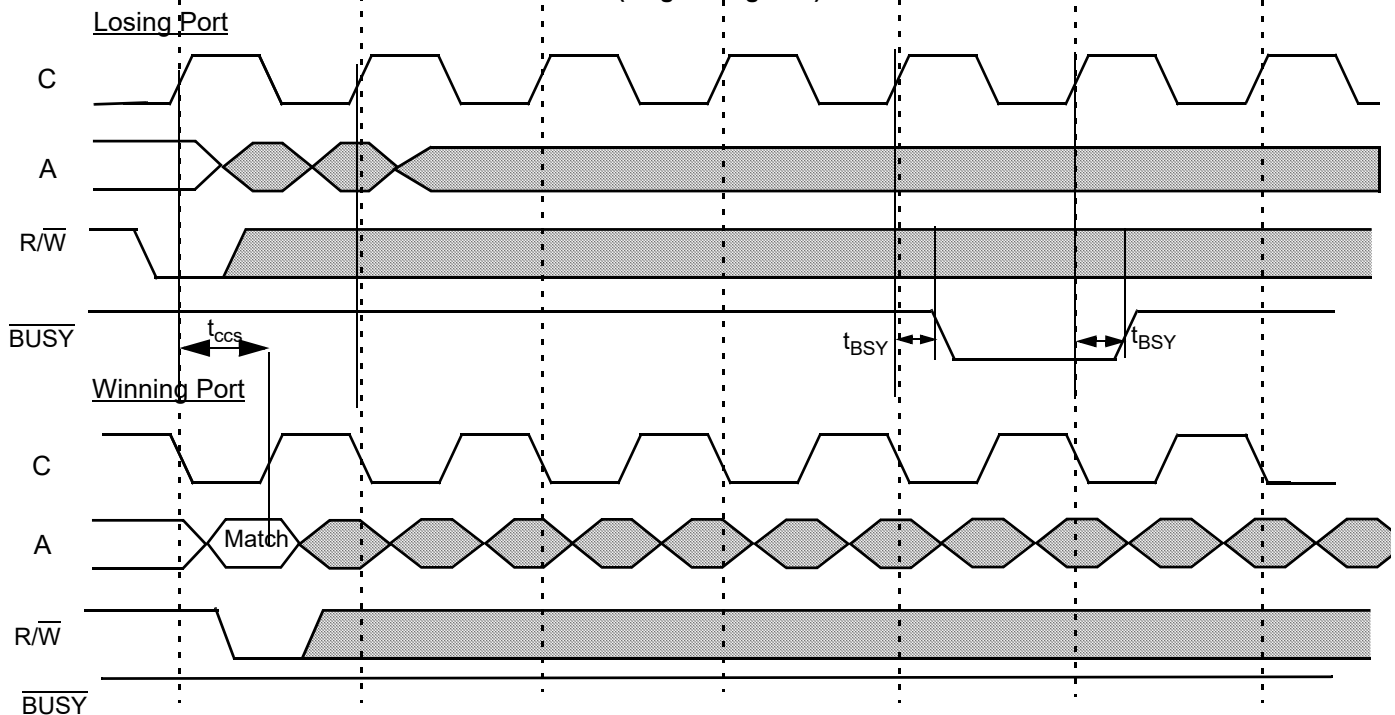
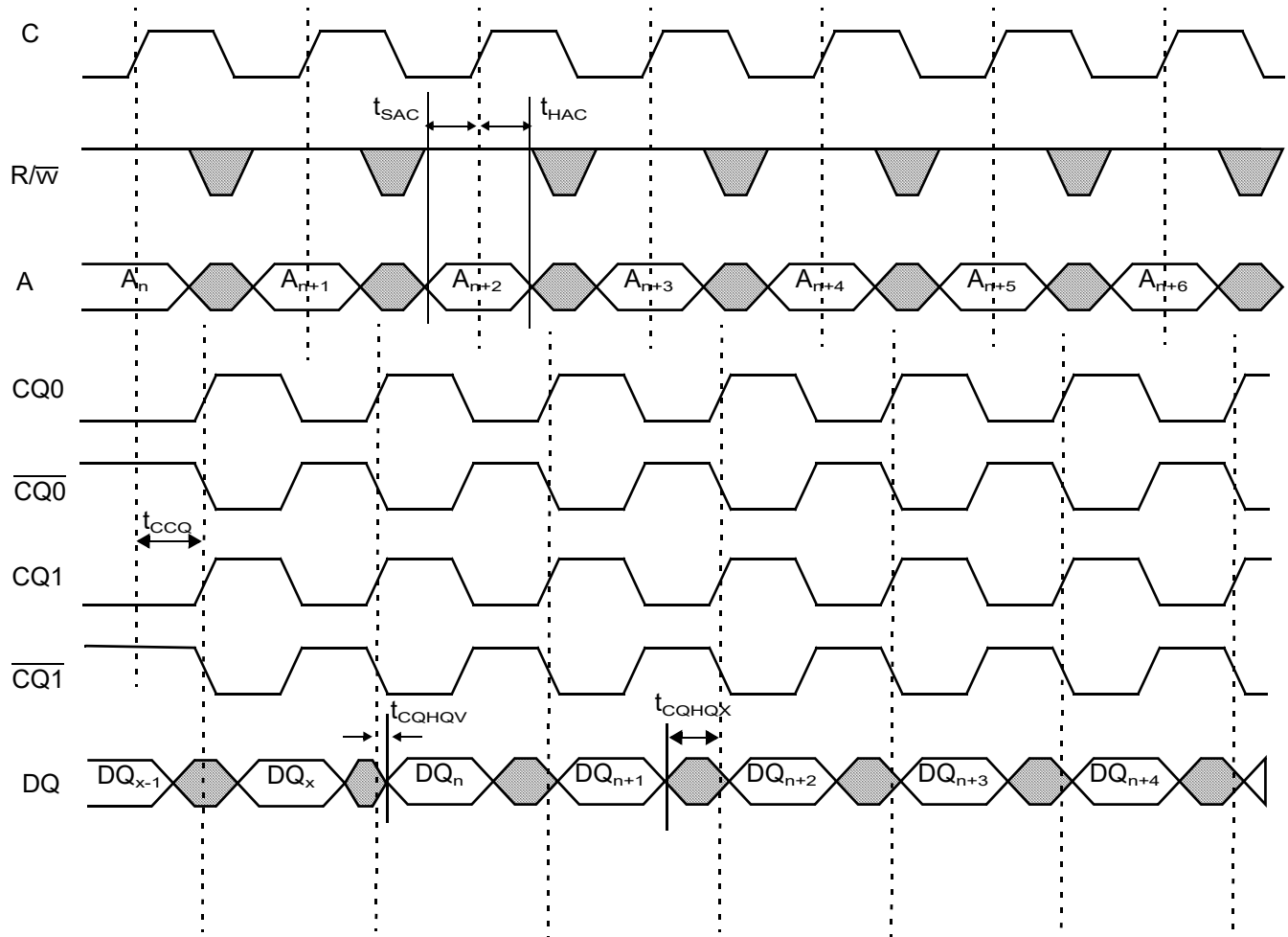


Figure 31. BUSY Timing, WRITE-WRITE Collision for Pipelined and Flow through Modes, Clock Timing Meets t_{CCS} . (Flag Losing Port)

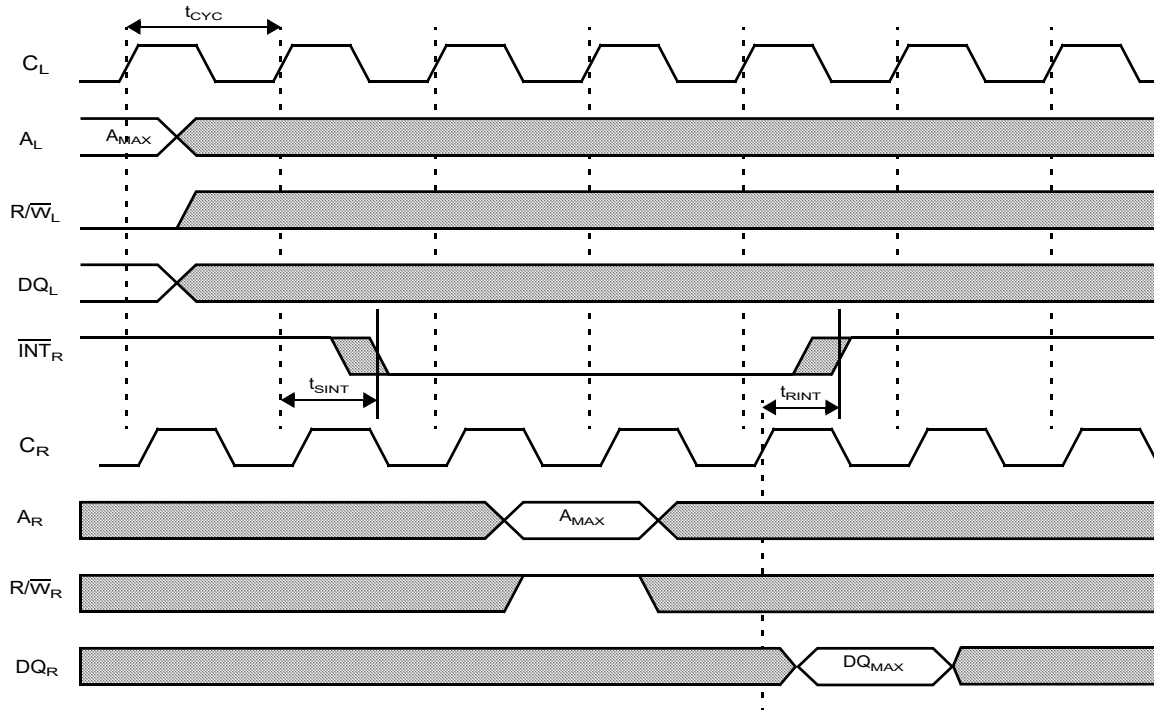


Switching Waveforms *(continued)*

Figure 32. Read with Echo Clock for Pipelined Mode (CQEN = HIGH)



Switching Waveforms (continued)

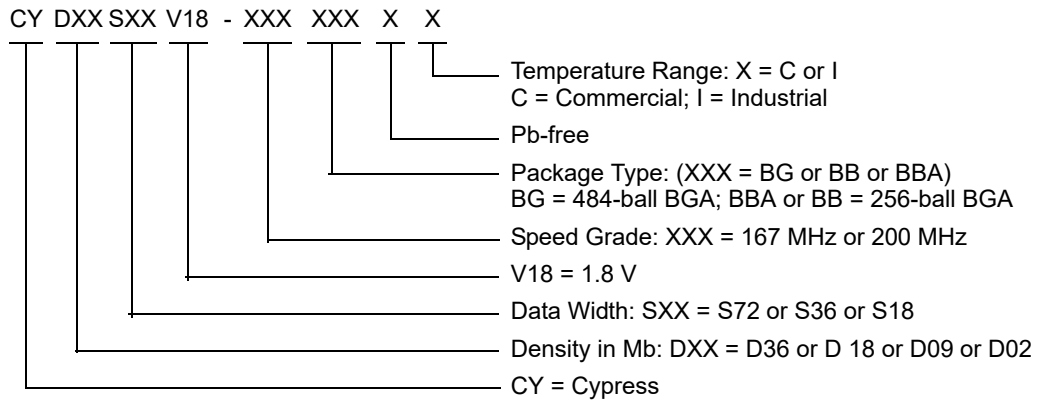
Figure 33. Mailbox Interrupt Output


Ordering Information

Speed (MHz)	Ordering Code	Package Diagram	Package Type	Operating Range
512K × 72 (36-Mbit) 1.8 V/1.5 V Synchronous CYD36S72V18 Dual-Port SRAM				
200	CYD36S72V18-200BGXC	001-07825	484-ball Ball Grid Array 27 mm × 27 mm with 1.0 mm pitch (Pb-free)	Commercial
256K × 72 (18-Mbit) 1.8 V/1.5 V Synchronous CYD18S72V18 Dual-Port SRAM				
200	CYD18S72V18-200BGXI	51-85218	484-ball Ball Grid Array 23 mm × 23 mm with 1.0 mm pitch (Pb-free)	Industrial
200	CYD18S72V18-200BGI	51-85218	484-ball Ball Grid Array 23 mm × 23 mm with 1.0 mm pitch	Industrial
167	CYD18S72V18-167BGI	51-85218	484-ball Ball Grid Array 23 mm × 23 mm with 1.0 mm pitch	Industrial
128K × 72 (9-Mbit) 1.8 V/1.5 V Synchronous CYD09S72V18 Dual-Port SRAM				
167	CYD09S72V18-167BBXC	51-85218	484-ball Ball Grid Array 23 mm × 23 mm with 1.0 mm pitch (Pb-free)	Commercial
1024K × 36 (36-Mbit) 1.8 V/1.5 V Synchronous CYD36S36V18 Dual-Port SRAM				
167	CYD36S36V18-167BGXI	001-07825	484-ball Ball Grid Array 27 mm × 27 mm with 1.0 mm pitch (Pb-free)	Industrial
512K × 36 (18-Mbit) 1.8 V/1.5 V Synchronous CYD18S36V18 Dual-Port SRAM				
200	CYD18S36V18-200BBAXI	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch (Pb-free)	Industrial
167	CYD18S36V18-167BBAI	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch	Industrial
256K × 36 (9-Mbit) 1.8 V/1.5 V Synchronous CYD09S36V18 Dual-Port SRAM				
200	CYD09S36V18-200BBXI	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch (Pb-free)	Industrial
167	CYD09S36V18-167BBXC	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch (Pb-free)	Commercial
64K × 36 (2-Mbit) 1.8 V or 1.5 V Synchronous CYD02S36V18 Dual-Port SRAM				
200	CYD02S36V18-200BBXC	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch (Pb-free)	Commercial
2048K × 18 (36-Mbit) 1.8 V/1.5 V Synchronous CYD36S18V18 Dual-Port SRAM				
167	CYD36S18V18-167BGXI	001-07825	484-ball Ball Grid Array 27 mm × 27 mm with 1.0 mm pitch (Pb-free)	Industrial
1024K × 18 (18-Mbit) 1.8 V/1.5 V Synchronous CYD18S18V18 Dual-Port SRAM				
200	CYD18S18V18-200BBAXI	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch (Pb-free)	Industrial
200	CYD18S18V18-200BBAXC	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch (Pb-free)	Commercial
167	CYD18S18V18-167BBAXI	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch (Pb-free)	Industrial
512K × 18 (9-Mbit) 1.8 V/1.5 V Synchronous CYD09S18V18 Dual-Port SRAM				
167	CYD09S18V18-167BBXI	51-85108	256-ball Ball Grid Array 17 mm × 17 mm with 1.0 mm pitch (Pb-free)	Industrial

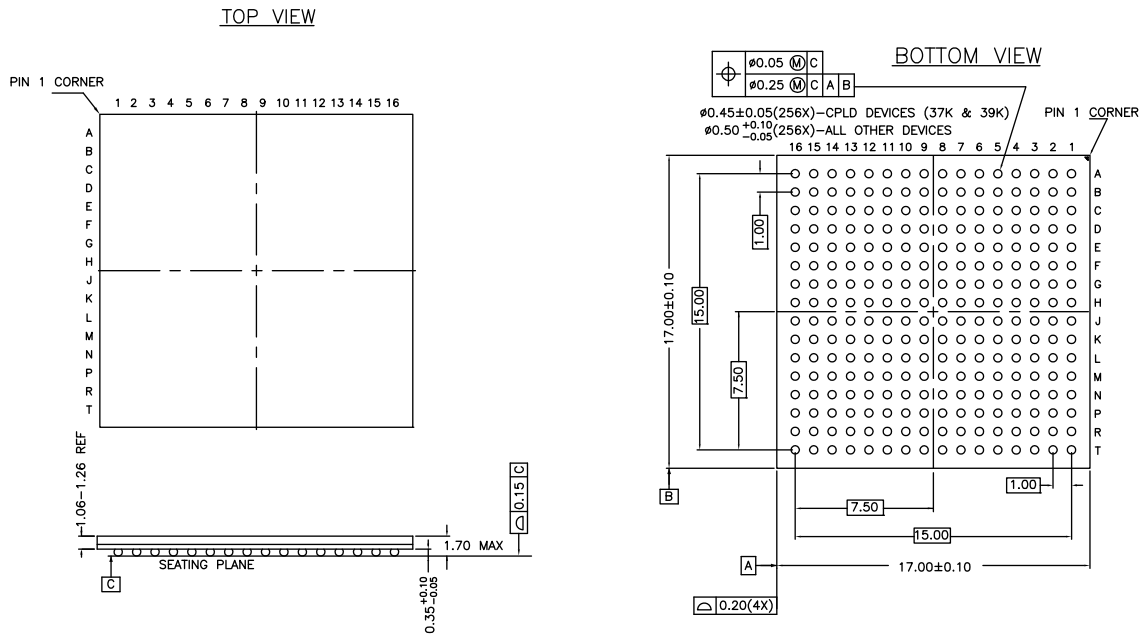


Ordering Code Definitions



Package Diagrams

Figure 34. 256-ball FBGA (17 × 17 × 1.7 mm) BB256/BW0BD Package Outline, 51-85108



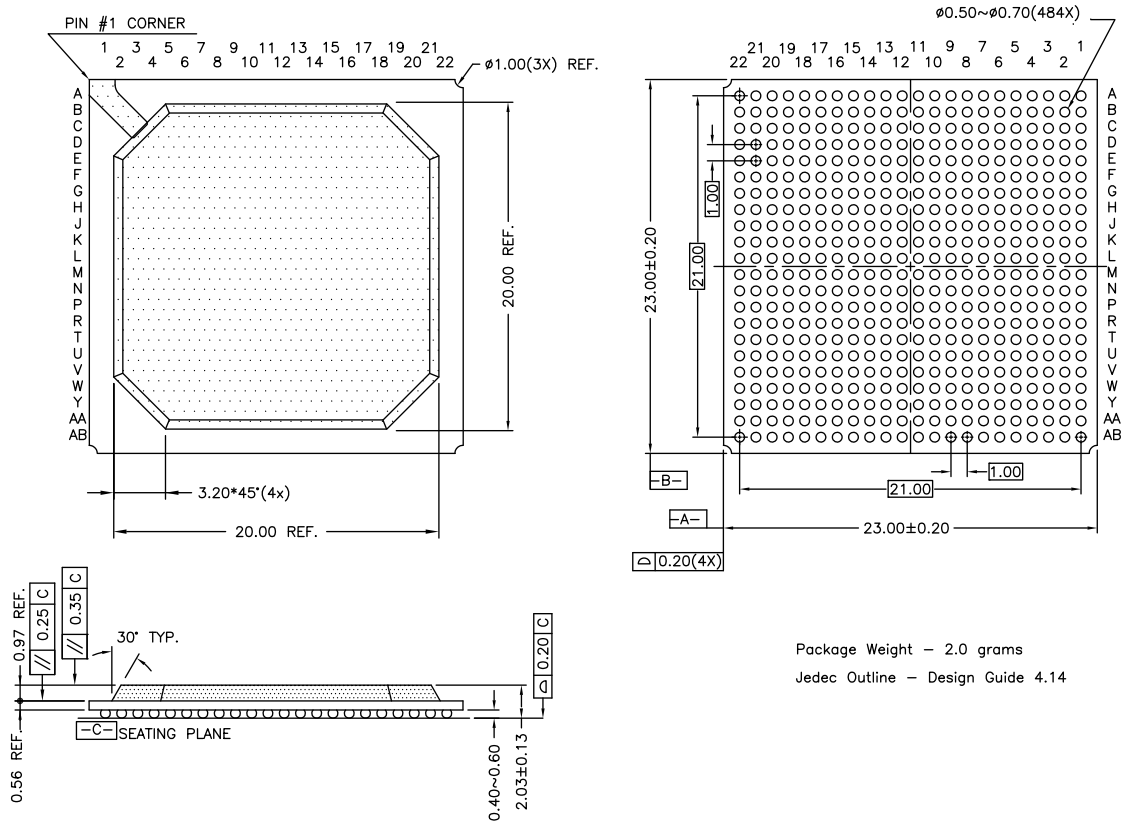
REFERENCE JEDEC MO-192

PACKAGE WEIGHT – 0.95gr

51-85108 *J

Package Diagrams *(continued)*

Figure 35. 484-ball PBGA (23 × 23 × 2.03 mm) BY484 Package Outline, 51-85218

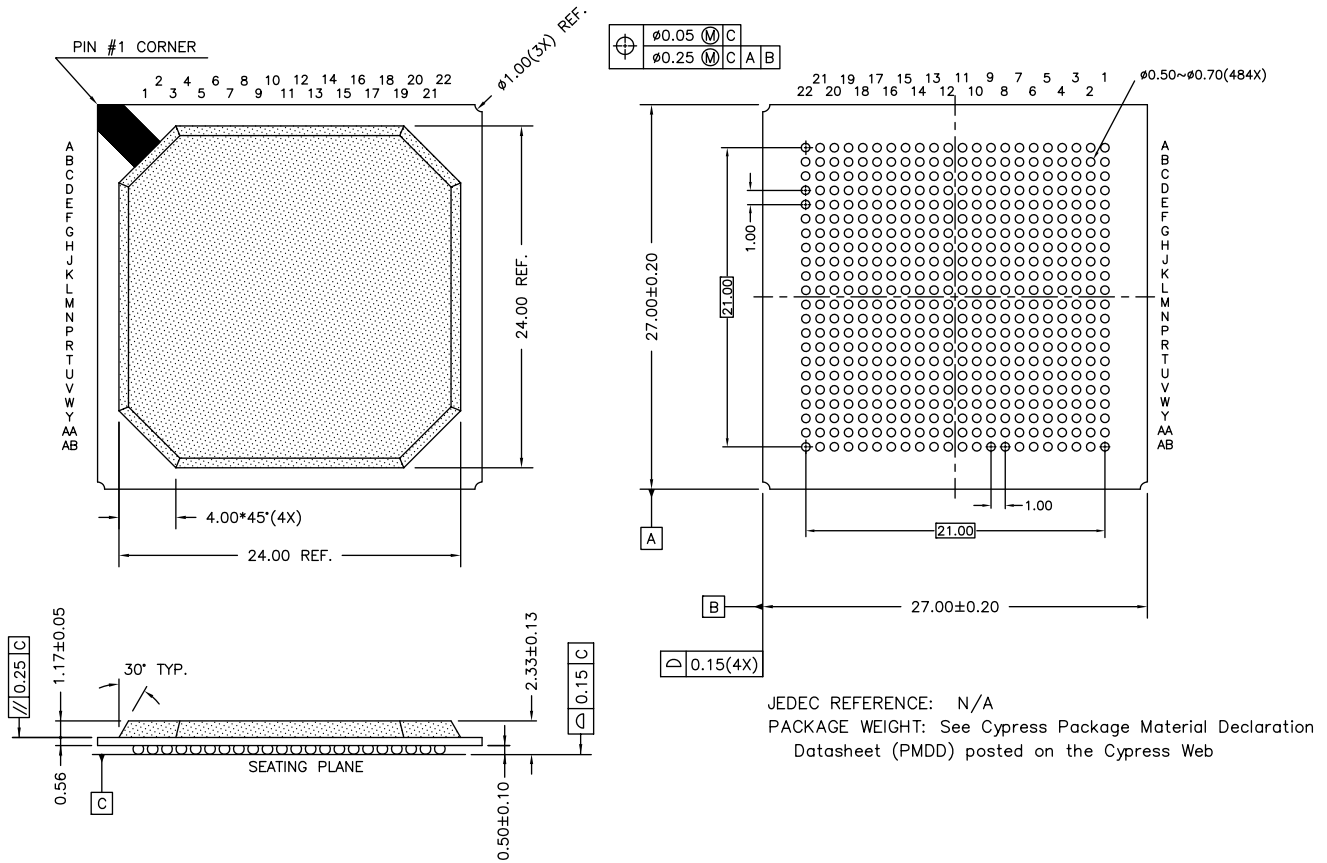


Package Weight - 2.0 grams
 Jedec Outline - Design Guide 4.14

51-85218 *C

Package Diagrams *(continued)*

Figure 36. 484-ball PBGA (27 × 27 × 2.33 mm) BY484S Package Outline, 001-07825



001-07825 *C

Acronyms

Acronym	Description
BGA	Ball Grid Array
CMOS	Complementary Metal Oxide Semiconductor
DLL	Delay Lock Loop
FBGA	Fine-Pitch Ball Grid Array
HSTL	High Speed Transceiver Logic
I/O	Input/Output
SDR	Single Data Rate
SRAM	Static Random Access Memory
TCK	Test Clock
TDI	Test Data-In
TDO	Test Data-Out
TMS	Test Mode Select
VIM	Variable Impedance Matching

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
MHz	megahertz
μA	microampere
mA	milliampere
ms	millisecond
mV	millivolt
ns	nanosecond
pF	picofarad
V	volt
W	watt

Document History Page

Document Title: CYDXXS72V18/CYDXXS36V18/CYDXXS18V18, FullFlex™ Synchronous SDR Dual-Port SRAM Document Number: 38-06082				
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
**	302411	YDT	See ECN	New data sheet.
*A	334036	YDT	See ECN	Corrected typo on page 1 Reproduced PDF file to fix formatting errors
*B	395800	SPN	See ECN	Added statement about no echo clocks for flow through mode Updated electrical characteristics Added note 16 and 17 (1.5 V timing) Added note 33 (timing for x18 devices) Updated input edge rate (note 34) Updated table 5 on deterministic access control logic Added description of busy readback in deterministic access control section Changed dummy write descriptions Updated ZQ pins connection details Updated note 24, B0 to BE0 Added power supply requirements to $\overline{\text{MRST}}$ and VC_SEL Added note 4 (VIM disable) Updated supply voltage to ground potential to 4.1 V Updated parameters on table 15 Updated and added parameters to table 16 Updated x72 pinout to SDR only pinout Updated 484 PBGA pin diagram Updated the pin definition of $\overline{\text{MRST}}$ Updated the pin definition of VC_SEL Updated READY description to include Wired OR note Updated master reset to include wired OR note for $\overline{\text{READY}}$ Updated minimum V_{OH} value for the 1.8 V LVCMOS configuration Updated electrical characteristics to include I_{OH} and I_{OL} values Updated electrical characteristics to include $\overline{\text{READY}}$ Added I_{IX3} Updated maximum input capacitance Added Notes 33 and 34 Removed Notes 15 and 17 Updated Pin Definitions for CQ0, CQ0, CQ1, and CQ1 Removed -100 Speed bin from Selection Guide Changed voltage name from V_{DDQ} to V_{DDIO} Changed voltage name from V_{DD} to V_{CORE} Moved the Mailbox Interrupt Timing Diagram to be the final timing diagram Updated the Package Type for the CYD36S18V18 parts Updated the Package Type for the CYD36S18V18 parts Updated the Package Type for the CYD18S18V18 parts Updated the Package Type for the CYD18S36V18 parts Included the Package Diagram for the 256-Ball FBGA (19 x 19 mm) BW256 Included an OE Controlled Write for Flow through Mode Switching Waveform Included a Read with Echo Clock Switching Waveform Updated Figure 5 and Figure 6 Updated Electrical Characteristics for $\overline{\text{READY}}$ V_{OH} and $\overline{\text{READY}}$ V Updated Electrical Characteristics for V_{OH} and V_{OL} for the -167 and -133 speeds Included a Unit column for Table 5 Removed Switching Characteristic t_{CA} from chart Included t_{OHZ} in Switching Waveform OE Controlled Write for Pipelined Mode Included t_{CKLZ2} in Waveform Read-to-Write-to-Read for Flow through Mode

Document History Page *(continued)*

Document Title: CYDXXS72V18/CYDXXS36V18/CYDXXS18V18, FullFlex™ Synchronous SDR Dual-Port SRAM Document Number: 38-06082				
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
*C	402238	KGH	SEE ECN	Updated AC Test Load and Waveforms Included FullFlex36 SDR 484-Ball BGA Pinout (Top View) Included FullFlex18 SDR 484-Ball BGA Pinout (Top View) Included Timing Parameter t_{CORDY}
*D	458131	YDT	SEE ECN	Changed ordering information with Pb-free part numbers Removed VC_SEL Added IO and core voltage adders Removed references to bin drop for LVTTL/2.5 V LVCMOS and 1.5 V core modes Updated Cin and Cout Updated ICC, ISB1, ISB2 and ISB3 tables Updated busy address read back timing diagram Added HTSL input waveform Removed HSTL (AC) from DC tables Added 484-ball 27 mm × 27 mm × 2.33 mm PBGA package
*E	470031	YDT	SEE ECN	Changed VOL of 1.8 V LVCMOS to 0.45 V Updated tRSF VREF is DNU when HSTL is not used Formatted pin description table Changed VDDIO pins for 36M × 36 and 36M × 18 pinouts Changed 36M × 72 JTAG IDCODE
*F	500001	YDT	SEE ECN	DLL Change, added Clock Input Cycle to Cycle Jitter Modified DLL description Changed Input Capacitance Table Changed tCCS number Added note 31
*G	627539	QSL	SEE ECN	change all NC to DNU corrected switching waveform for (CQEN = High) from both Pipeline and Flow through mode to only pipeline mode Modified master reset description Modified switching characteristics tables, extracted signals effected by the DLL into one table and combine all other signals into one table updated package name Added footnote for tHD, tHAC and tSAC changed note 26 description
*H	2505003	VKN / AESA	See ECN	Modified footnote #1 Removed 250 MHz speed bin Added 2-Mbit part and it's related information Changed ball name ZQ1 to DNU for 18M and lesser density devices Added 256-ball (17 × 17 mm) BGA package for 18M Made PORTSTD[1:0] left and right pins driven only by LVTTL reference level For 1.8 V LVCMOS level, Changed $V_{IH(min)}$ from 1.26 V to 0.65 times V_{DDIO} and changed $V_{IL(max)}$ from 0.36 V to 0.35 times V_{DDIO} Changed tHD, tHAC specs for 36M from 0.6 ns/0.7 ns to 0.8 ns (See footnote# 32) Updated Ordering Information table

Document History Page *(continued)*

Document Title: CYDXXS72V18/CYDXXS36V18/CYDXXS18V18, FullFlex™ Synchronous SDR Dual-Port SRAM Document Number: 38-06082				
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
*I	2898491	RAME	07/01/2010	Modified "Counter Load Operation" section on page 12 and in Table7 on page 13. Corrected typo in Table 14. by making $\overline{\text{LowSPD}} = 0$ for t_{CD1} spec in the description. Modified figure 16. on page 30. Removed inactive parts from Ordering Information. Updated Packaging Information. Corrected "Counter Interrupt operation" Section in Page 14 of the data sheet Updated ordering information with the parts, CYD02S36V18-200BBC and CYD36S72V18-167BGI.
*J	2995098	RAME	07/28/2010	Updated Ordering Information : Updated part numbers. Added Ordering Code Definitions . Added Acronyms and Units of Measure . Minor edits.
*K	3267210	ADMU	05/26/2011	Removed information for 4Mb devices. Updated Electrical Characteristics on page 21 (Removed 133 MHz speed bin). Updated Switching Characteristics on page 25 (Removed 133 MHz speed bin). Updated Ordering Information : Updated part numbers.
*L	3357888	ADMU	08/30/2011	Updated Pin configuration Figure 1 through 5. Added Thermal Resistance .
*M	3349458	ADMU	10/28/2011	Minor edits in Figure 5 (removed overbars in balls C5 and C12). Updated Package Diagrams .
*N	3845411	ADMU	01/29/2013	Updated Ordering Information (Updated part numbers). Updated Package Diagrams : spec 001-07825 – Changed revision from *A to *B.
*O	3895845	ADMU	02/05/2013	Updated Ordering Information (Updated part numbers).
*P	4413766	ADMU	06/19/2014	Updated Package Diagrams : spec 51-85218 – Changed revision from *A to *B. Updated to new template.
*Q	4581625	ADMU	11/27/2014	Updated Functional Description : Added "For a complete list of related documentation, click here ." at the end.
*R	5787387	NILE	06/27/2017	Updated Ordering Information : Updated part numbers. Updated Package Diagrams : spec 51-85108 – Changed revision from *I to *J. spec 51-85218 – Changed revision from *B to *C. spec 001-07825 – Changed revision from *B to *C. Updated to new template. Completing Sunset Review.
*S	6259481	NILE	07/24/2018	Added a footnote about removal of support to HSTL signalling in these products from WW1830.

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